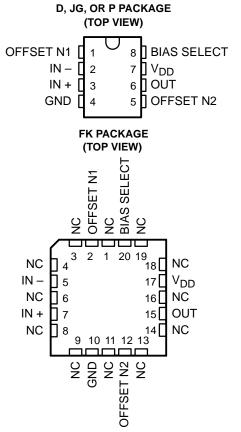
- Input Offset Voltage Drift . . . Typically 0.1 μV/Month, Including the First 30 Days
- Wide Range of Supply Voltages Over Specified Temperature Range:

0°C to 70°C . . . 3 V to 16 V -40°C to 85°C . . . 4 V to 16 V -55°C to 125°C . . . 5 V to 16 V

- Single-Supply Operation
- Common-Mode Input Voltage Range Extends Below the Negative Rail (C-Suffix and I-Suffix Types)
- Low Noise . . . 25 nV/√Hz Typically at f = 1 kHz (High-Bias Mode)
- Output Voltage Range Includes Negative Rail
- High Input Impedance . . . $10^{12} \Omega$ Typ
- ESD-Protection Circuitry
- Small-Outline Package Option Also Available in Tape and Reel
- Designed-In Latch-Up Immunity

description

The TLC271 operational amplifier combines a wide range of input offset voltage grades with low offset voltage drift and high input impedance. In addition, the TLC271 offers a bias-select mode



NC - No internal connection

that allows the user to select the best combination of power dissipation and ac performance for a particular application. These devices use Texas Instruments silicon-gate LinCMOS™ technology, which provides offset voltage stability far exceeding the stability available with conventional metal-gate processes.

AVAILABLE OPTIONS

	V may	PACKAGE						
TA	V _{IO} max AT 25°C	SMALL OUTLINE (D)	CHIP CARRIER (FK)	CERAMIC DIP (JG)	PLASTIC DIP (P)			
0°C to 70°C	2 mV 5 mV 10 mV	TLC271BCD TLC271ACD TLC271CD	_	_	TLC271BCP TLC271ACP TLC271CP			
-40°C to 85°C	2 mV 5 mV 10 mV	TLC271BID TLC271AID TLC271ID	_	_	TLC271BIP TLC271AIP TLC271IP			
-55°C to 125°C	10 mV	TLC271MD	TLC271MFK	TLC271MJG	TLC271MP			

The D package is available taped and reeled. Add R suffix to the device type (e.g., TLC271BCDR).



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DEVICE FEATURES

DADAMETED†	BIA	UNIT		
PARAMETER†	HIGH	MEDIUM	LOW	UNIT
PD	3375	525	50	μW
SR	3.6	0.4	0.03	V/μs
v _n	25	32	68	nV/√ Hz
B ₁	1.7	0.5	0.09	MHz
AVD	23	170	480	V/mV

[†] Typical at $V_{DD} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

description (continued)

Using the bias-select option, these cost-effective devices can be programmed to span a wide range of applications that previously required BiFET, NFET, or bipolar technology. Three offset voltage grades are available (C-suffix and I-suffix types), ranging from the low-cost TLC271 (10 mV) to the TLC271B (2 mV) low-offset version. The extremely high input impedance and low bias currents, in conjunction with good common-mode rejection and supply voltage rejection, make these devices a good choice for new state-of-the-art designs as well as for upgrading existing designs.

In general, many features associated with bipolar technology are available in LinCMOS™ operational amplifiers, without the power penalties of bipolar technology. General applications such as transducer interfacing, analog calculations, amplifier blocks, active filters, and signal buffering are all easily designed with the TLC271. The devices also exhibit low-voltage single-supply operation, making them ideally suited for remote and inaccessible battery-powered applications. The common-mode input voltage range includes the negative rail.

A wide range of packaging options is available, including small-outline and chip-carrier versions for high-density system applications.

The device inputs and output are designed to withstand –100-mA surge currents without sustaining latch-up.

The TLC271 incorporates internal ESD-protection circuits that prevent functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2; however, care should be exercised in handling these devices as exposure to ESD may result in the degradation of the device parametric performance.

The C-suffix devices are characterized for operation from 0° C to 70° C. The I-suffix devices are characterized for operation from -40° C to 85° C. The M-suffix devices are characterized for operation over the full military temperature range of -55° C to 125° C.

bias-select feature

The TLC271 offers a bias-select feature that allows the user to select any one of three bias levels depending on the level of performance desired. The tradeoffs between bias levels involve ac performance and power dissipation (see Table 1).

Table 1. Effect of Bias Selection on Performance

	TYPICAL PARAMETER VALUES		MODE						
	T _A = 25°C, V _{DD} = 5 V	HIGH BIAS $R_L = 10 \text{ k}\Omega$	MEDIUM BIAS $R_L = 100 \text{ k}\Omega$	LOW BIAS $R_L = 1 M\Omega$	UNIT				
P_{D}	Power dissipation	3.4	0.5	0.05	mW				
SR	Slew rate	3.6	0.4	0.03	V/μs				
٧n	Equivalent input noise voltage at f = 1 kHz	25	32	68	nV/√Hz				
B ₁	Unity-gain bandwidth	1.7	0.5	0.09	MHz				
φm	Phase margin	46°	40°	34°					
AVD	Large-signal differential voltage amplification	23	170	480	V/mV				



bias selection

Bias selection is achieved by connecting the bias select pin to one of three voltage levels (see Figure 1). For medium-bias applications, it is recommended that the bias select pin be connected to the midpoint between the supply rails. This procedure is simple in split-supply applications, since this point is ground. In single-supply applications, the medium-bias mode necessitates using a voltage divider as indicated in Figure 1. The use of large-value resistors in the voltage divider reduces the current drain of the divider from the supply line. However, large-value resistors used in conjunction with a large-value capacitor require significant time to charge up to the supply midpoint after the supply is switched on. A voltage other than the midpoint can be used if it is within the voltages specified in Figure 1.

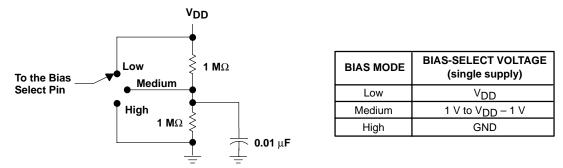


Figure 1. Bias Selection for Single-Supply Applications

high-bias mode

In the high-bias mode, the TLC271 series features low offset voltage drift, high input impedance, and low noise. Speed in this mode approaches that of BiFET devices but at only a fraction of the power dissipation. Unity-gain bandwidth is typically greater than 1 MHz.

medium-bias mode

The TLC271 in the medium-bias mode features low offset voltage drift, high input impedance, and low noise. Speed in this mode is similar to general-purpose bipolar devices but power dissipation is only a fraction of that consumed by bipolar devices.

TLC271, TLC271A, TLC271B LinCMOS™ PROGRAMMABLE LOW-POWER OPERATIONAL AMPLIFIERS

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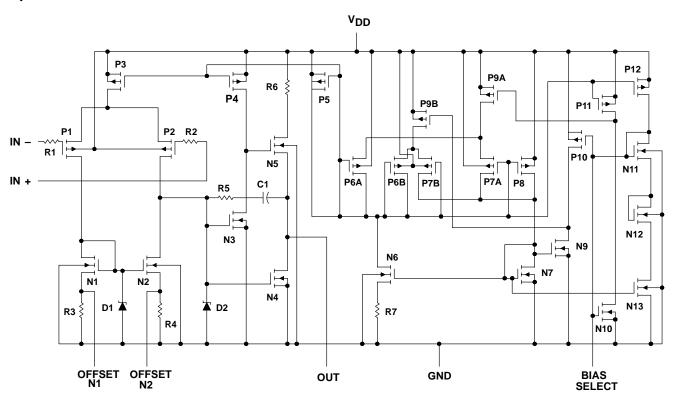
low-bias mode

In the low-bias mode, the TLC271 features low offset voltage drift, high input impedance, extremely low power consumption, and high differential voltage gain.

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equivalent schematic





absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage, V _{DD} (see Note 1)	
Differential input voltage, V _{ID} (see Note 2)	±V _{DD}
Input voltage range, V _I (any input)	– 0.3 V to V _{DD}
Input current, I ₁	±5 mA
Output current, I _O	±30 mA
Duration of short-circuit current at (or below) 25°C (see Note 3)	
Continuous total dissipation	
Operating free-air temperature, T _A : C suffix	0°C to 70°C
I suffix	– 40°C to 85°C
M suffix	– 55°C to 125°C
Storage temperature range	– 65°C to 150°C
Case temperature for 60 seconds: FK package	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: D or P pa	ackage 260°C
Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds: JG packa	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values, except differential voltages, are with respect to network ground.
 - 2. Differential voltages are at IN+ with respect to IN-.
 - 3. The output may be shorted to either supply. Temperature and/or supply voltages must be limited to ensure that the maximum dissipation rating is not exceeded (see application section).

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
D	725 mW	5.8 mW/°C	464 mW	377 mW	145 mW
FK	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW
JG	1050 mW	8.4 mW/°C	672 mW	546 mW	210 mW
Р	1000 mW	8.0 mW/°C	640 mW	520 mW	200 mW

recommended operating conditions

		C SUFFIX		I SUFFIX		M SU	UNIT	
	MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
Supply voltage, V _{DD}		3	16	4	16	5	16	V
Common mode input voltage Vie	V _{DD} = 5 V	-0.2	3.5	-0.2	3.5	0	3.5	V
Common-mode input voltage, V _{IC}	V _{DD} = 10 V	-0.2	8.5	-0.2	8.5	0	8.5	
Operating free-air temperature, T _A		0	70	-40	85	-55	125	°C



electrical characteristics at specified free-air temperature (unless otherwise noted)

			TEOT		Т	LC2710	, TLC27	1AC, TL	C271BC		
	PARAMETER		TEST CONDITIONS	T _A †	V	_{DD} = 5 \	<i>'</i>	۷	_D = 10	٧	UNIT
			CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
		TLC271C		25°C		1.1	10		1.1	10	
		11.02/10	V _O = 1.4 V,	Full range			12			12	
\/. -	lanut offeet voltege	TLC271AC	V _{IC} = 0 V,	25°C		0.9	5		0.9	5	\
VIO	Input offset voltage	ILC2/ IAC	$R_S = 50 \Omega$,	Full range			6.5			6.5	mV
		TLC271BC	$R_L = 10 \text{ k}\Omega$	25°C		0.34	2		0.39	2	
		TLC27 IBC		Full range			3			3	
ανιο	Average temperature of input offset voltage	coefficient		25°C to 70°C		1.8			2		μV/°C
1	Input offset surrent (se	oo Noto 4)	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	n.A
IO	Input offset current (se	ee Note 4)	$V_{IC} = V_{DD}/2$	70°C		7	300		7	300	pА
	Input bigg ourrent (age	Note 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	n.A
ΙΒ	Input bias current (see	e Note 4)	$V_{IC} = V_{DD}/2$	70°C		40	600		50	600	pА
	C	valta a a		25°C	-0.2 to 4	-0.3 to 4.2		-0.2 to 9	-0.3 to 9.2		٧
VICR	/ICR Common-mode input voltage range (see Note 5)			Full range	-0.2 to 3.5			-0.2 to 8.5			V
				25°C	3.2	3.8		8	8.5		
Vон	High-level output volta	age	$V_{ID} = 100 \text{ mV},$ $R_L = 10 \text{ k}\Omega$	0°C	3	3.8		7.8	8.5		V
				70°C	3	3.8		7.8	8.4		
				25°C		0	50		0	50	mV
VOL	Low-level output volta	ge	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 0$	0°C		0	50		0	50	
			IOL = 0	70°C		0	50		0	50	
			2 4010	25°C	5	23		10	36		
A_{VD}	Large-signal differenti- voltage amplification	al	$R_L = 10 \text{ k}\Omega$, See Note 6	0°C	4	27		7.5	42		V/mV
	voitago ampimoation		000 11010 0	70°C	4	20		7.5	32		
				25°C	65	80		65	85		
CMRR	Common-mode reject	ion ratio	V _{IC} = V _{ICR} min	0°C	60	84		60	88		dB
				70°C	60	85		60	88		
				25°C	65	95		65	95		
k _{SVR}	Supply-voltage rejection (ΔV _{DD} /ΔV _{IO})	on ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V}$ $V_{O} = 1.4 \text{ V}$	0°C	60	94		60	94		dB
	(A V DD / A V IO /		VU = 1.4 V	70°C	60	96		60	96		
I _{I(SEL)}	Input current (BIAS SI	ELECT)	V _{I(SEL)} = 0	25°C		-1.4			-1.9		μΑ
			$V_O = V_{DD}/2$,	25°C		675	1600		950	2000	_
I _{DD}	Supply current		V _I C = V _{DD} /2, V _I C = V _{DD} /2,	0°C		775	1800		1125	2200	
				70°C		575	1300		750	1700	

[†] Full range is 0°C to 70°C.

- 5. This range also applies to each input individually.
- 6. At V_{DD} = 5 V, V_{O} = 0.25 V to 2 V; at V_{DD} = 10 V, V_{O} = 1 V to 6 V.



electrical characteristics at specified free-air temperature (unless otherwise noted)

			TEST			TLC271I, TLC271AI, TLC271BI						
	PARAMETER		TEST CONDITIONS	T _A †	V	_{DD} = 5 \	/	۷	_{OD} = 10	V	UNIT	
			CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX		
		TLC2711		25°C		1.1	10		1.1	10		
		ILC2/11	V _O = 1.4 V,	Full range			13			13		
\/. -	Innut offeet veltere	TI C074 AI	V _{IC} = 0 V,	25°C		0.9	5		0.9	5	\/	
VIO	Input offset voltage	TLC271AI	$R_S = 50 \Omega$	Full range			7			7	mV	
		TLC271BI	$R_L = 10 \text{ k}\Omega$	25°C		0.34	2		0.39	2		
		TLO27 IBI		Full range			3.5			3.5		
αΝΙΟ	Average temperature of input offset voltage	coefficient		25°C to 85°C		1.8			2		μV/°C	
li o	Input offset current (se	no Noto 4)	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	pА	
lio	input onset current (se	ee Note 4)	$V_{IC} = V_{DD}/2$	85°C		24	1000		26	1000	PΑ	
	Input bigg ourrent (age	Note 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	nΛ	
lΒ	Input bias current (see	e Note 4)	$V_{IC} = V_{DD}/2$	85°C		200	2000		220	2000	pΑ	
				25°C	-0.2 to	-0.3 to		-0.2 to	-0.3 to		V	
\/	Common-mode input				4	4.2		9	9.2			
VICR	VICR voltage range (see Note 5)			Full range	-0.2 to 3.5			-0.2 to 8.5			V	
				25°C	3.2	3.8		8	8.5			
VOH	High-level output volta	ige	V _{ID} = 100 mV,	-40°C	3	3.8		7.8	8.5		V	
	3 - 1 - 1 - 1 - 1 - 1 - 1 - 1		$R_L = 10 \text{ k}\Omega$	85°C	3	3.8		7.8	8.5			
				25°C		0	50		0	50	mV	
VOL	Low-level output volta	ge	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 0$	-40°C		0	50		0	50		
			IOL = 0	85°C		0	50		0	50		
			_	25°C	5	23		10	36			
AVD	Large-signal differentiation	al	R_L = 10 kΩ, See Note 6	−40°C	3.5	32		7	46		V/mV	
	voltage amplification		Occ Note o	85°C	3.5	19		7	31			
				25°C	65	80		65	85			
CMRR	Common-mode rejecti	ion ratio	V _{IC} = V _{ICR} min	-40°C	60	81		60	87		dB	
				85°C	60	86		60	88			
				25°C	65	95		65	95			
k _{SVR}	Supply-voltage rejection (ΔV _{DD} /ΔV _{IO})	on ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V}$ $V_{O} = 1.4 \text{ V}$	-40°C	60	92		60	92		dB	
	(= 1 DD / 2 1 D/		VO = 1.4 V	85°C	60	96		60	96		<u>1</u>	
I _I (SEL)	Input current (BIAS SE	ELECT)	V _{I(SEL)} = 0	25°C		-1.4			-1.9		μΑ	
			$V_O = V_{DD}/2$,	25°C		675	1600		950	2000	⊣	
I_{DD}	Supply current	Supply current	$V_{IC} = V_{DD}/2$, $-$	-40°C		950	2200		1375	2500		
			No load	85°C		525	1200		725	1600		

[†]Full range is –40°C to 85°C.

^{6.} At V_{DD} = 5 V, V_{O} = 0.25 V to 2 V; at V_{DD} = 10 V, V_{O} = 1 V to 6 V.



^{5.} This range also applies to each input individually.

electrical characteristics at specified free-air temperature (unless otherwise noted)

		TEOT				TLC2	71M			
	PARAMETER	TEST CONDITIONS	T _A †	V	_{DD} = 5 \	/	۷	_{OD} = 10 '	٧	UNIT
		CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
V _{IO}	Input offset voltage	V _O = 1.4 V, V _{IC} = 0 V,	25°C		1.1	10		1.1	10	mV
VIO	input onset voltage	$R_S = 50 \Omega$, $R_L = 10 k\Omega$	Full range			12			12	
αVIO	Average temperature coefficient of input offset voltage		25°C to 125°C		2.1			2.2		μV/°C
lio.	Input offset current (see Note 4)	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	pA
ΙΟ	input onset current (see Note 4)	$V_{IC} = V_{DD}/2$	125°C		1.4	15		1.8	15	nA
lin	Input bias current (see Note 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	pA
İΙΒ	input bias current (see Note 4)	$V_{IC} = V_{DD}/2$	125°C		9	35		10	35	nA
V	Common-mode input voltage		25°C	0 to 4	-0.3 to 4.2		0 to 9	-0.3 to 9.2		V
VICR	range (see Note 5)		Full range	0 to 3.5			0 to 8.5			V
		\/ 400 m\/	25°C	3.2	3.8		8	8.5		
Vон	High-level output voltage	$V_{ID} = 100 \text{ mV},$ $R_{I} = 10 \text{ k}\Omega$	−55°C	3	3.8		7.8	8.5		V
			125°C	3	3.8		7.8	8.4		
		V _{ID} = -100 mV, I _{OL} = 0	25°C		0	50		0	50	
VOL	Low-level output voltage		−55°C		0	50	-	0	50	mV
		OL 1	125°C		0	50		0	50	
	Large-signal differential	R _L = 10 kΩ,	25°C	5	23		10	36		
AVD	voltage amplification	See Note 6	−55°C	3.5	35		7	50		V/mV
			125°C	3.5	16		7	27		
			25°C	65	80		65	85		
CMRR	Common-mode rejection ratio	V _{IC} = V _{ICR} min	−55°C	60	81		60	87		dB
			125°C	60	84		60	86		
	Supply-voltage rejection ratio	V _{DD} = 5 V to 10 V	25°C	65	95		65	95		
ksvr	(ΔV _{DD} /ΔV _{IO})	V _O D = 5 V to 10 V V _O = 1.4 V	−55°C	60	90		60	90		dB
		_	125°C	60	97		60	97		
I _I (SEL)	Input current (BIAS SELECT)	V _{I(SEL)} = 0	25°C		-1.4			-1.9		μΑ
		$V_O = V_{DD}/2$,	25°C		675	1600		950	2000	μΑ
IDD	Supply current V	$V_{IC} = V_{DD}/2,$ –	−55°C		1000	2500		1475	3000	
+	'- FF00 to 40500	No load	125°C		475	1100		625	1400	

† Full range is -55°C to 125°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.

5. This range also applies to each input individually.

6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 10 \text{ V}$, $V_{O} = 1 \text{ V}$ to 6 V.



operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

PARAMETER		TEST CO	TEST CONDITIONS			TLC271C, TLC271AC, TLC271BC		
			_	TA	MIN	TYP	MAX	
				25°C		3.6		
			V _{I(PP)} = 1 V	0°C		4		
SR	Slow rate at unity gain	$R_L = 10 \text{ k}\Omega$		70°C		3		\//uo
SK	Slew rate at unity gain	C _L = 20 pF, See Figure 98		25°C		2.9		V/μs
			$V_{I(PP)} = 2.5 V$	0°C		3.1		
				70°C		2.5		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz
				25°C		320		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 10 \text{ k}\Omega$,	C _L = 20 pF, See Figure 98	0°C		340		kHz
		N_ = 10 K32,	Occ rigure 50	70°C		260		
				25°C		1.7		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 \text{ pF},$	0°C		2		MHz
		Occ riguic 100		70°C		1.3		
		V 40V	(5	25°C		46°		
φm	Phase margin	V _I = 10 mV, C _L = 20 pF,	t = B ₁ , See Figure 100	0°C		47°		
				70°C		44°		

PARAMETER		TEST CC	TEST CONDITIONS			TLC271C, TLC271AC, TLC271BC		
				TA	MIN	TYP	MAX	
				25°C		5.3		
			V _{I(PP)} = 1 V	0°C		5.9		
SR	Clause at units main	$R_L = 10 \text{ k}\Omega$		70°C		4.3		\//v.a
	Slew rate at unity gain	C _L = 20 p F, See Figure 98		25°C		4.6		V/μs
		3	$V_{I(PP)} = 5.5 V$	0°C		5.1		
				70°C		3.8		
V _n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz
				25°C		200		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 10 \text{ k}\Omega$,	C _L = 20 pF,	0°C		220		kHz
		N_ = 10 K32,	Occ rigure 30	70°C		140		
		.,		25°C		2.2		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 \text{ pF},$	0°C		2.5		MHz
		occ riguic 100		70°C		1.8		
		4 B	\\ 40 m\\	25°C		49°		
φm	Phase margin	f = B ₁ , C _L = 20 pF,	V _I = 10 mV, See Figure 100	0°C		50°		
		p.,		70°C		46°		

operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	PARAMETER	TEST CO	TEST CONDITIONS			TLC271I, TLC271AI, TLC271BI		
				MIN	TYP	MAX		
				25°C		3.6		
			V _{I(PP)} = 1 V	−40°C		4.5		
SR	Slew rate at unity gain	$R_L = 10 \text{ k}\Omega$, $C_L = 20 \text{ pF}$,		85°C		2.8		V/μs
J Six	Siew rate at unity gain	See Figure 98	V _{I(PP)} = 2.5 V	25°C		2.9		ν/μδ
				−40°C		3.5		
				85°C		2.3		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz
				25°C		320		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 10 \text{ k}\Omega$,	CL = 20 pF,	-40°C		380		kHz
		1\(\(\) = 10 \(\) \(\) (32,	See Figure 90	85°C		250		
				25°C		1.7		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	-40°C		2.6		MHz
·		Occ rigure 100		85°C		1.2		
)/ ₁ 40 m)/	4 D	25°C		46°		
φm		$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ , See Figure 100	-40°C		49°		
		-L p.,	22394.0	85°C		43°		

	PARAMETER	TEST CO	NDITIONS	TA	TLC271I, TLC271AI, TLC271BI			UNIT	
					MIN	TYP	MAX		
				25°C		5.3			
			V _{I(PP)} = 1 V	-40°C		6.8			
SR	Clausete et units anim	$R_L = 10 \text{ k}\Omega$, $C_L = 20 \text{ pF}$, See Figure 98		85°C		4		\//v.a	
SK	Slew rate at unity gain			25°C		4.6		V/μs	
			V _{I(PP)} = 5.5 V	−40°C		5.8			
				85°C		3.5			
V _n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz	
				25°C		200			
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 10 \text{ k}\Omega$,	C _L = 20 pF, See Figure 98		-40°C		260		kHz
				85°C		130			
				25°C		2.2			
В1	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	-40°C		3.1		MHz	
фm		Gee rigule 100		85°C		1.7			
		V 40V	, D	25°C		49°			
	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f= B ₁ , See Figure 100	-40°C		52°			
		,	ga.c	85°C		46°			



operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	DADAMETED	TEST CO	NDITIONS		Т	LC271M		LINUT
	PARAMETER	IESI CO	NDITIONS	TA	MIN	TYP	MAX	UNIT
				25°C		3.6		
			V _{I(PP)} = 1 V	−55°C		4.7		
SR	Clausesta at units main	$R_L = 10 \text{ k}\Omega$, $C_L = 20 \text{ pF}$, See Figure 98		125°C		2.3		\//v.a
J SK	Slew rate at unity gain		V _{I(PP)} = 2.5 V	25°C		2.9		V/μs
				−55°C		3.7		
				125°C		2		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz
				25°C		320		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH},$ $R_L = 10 \text{ k}\Omega,$	C _L = 20 pF, See Figure 98	−55°C		400		kHz
				125°C		230		
		.,,		25°C		1.7		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF,$	−55°C		2.9		MHz
	l ³			125°C		1.1		
		\/ 40 m\/	4 D	25°C		46°		
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ , See Figure 100	−55°C		49°		
		F.,		125°C		41°		

	DADAMETED	TEST CO	NDITIONS		T	LC271M		
	PARAMETER	IESI CO	NDITIONS	TA	MIN	TYP	MAX	UNIT
				25°C		5.3		
			V _{I(PP)} = 1 V	−55°C		7.1		
SR	Slow rate at unity gain	$R_L = 10 \text{ k}\Omega$, $C_L = 20 \text{ pF}$, See Figure 98		125°C		3.1		1//110
J SK	Slew rate at unity gain			25°C		4.6		V/μs
			$V_{I(PP)} = 5.5 V$	−55°C		6.1		
				125°C		2.7		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		25		nV/√ Hz
	Maximum output-swing bandwidth			25°C		200		
ВОМ		$V_O = V_{OH},$ $R_L = 10 \text{ k}\Omega,$	C _L = 20 pF, See Figure 98	−55°C		280		kHz
				125°C		110		
				25°C		2.2		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	−55°C		3.4		MHz
		occ rigure 100		125°C		1.6		
		, ,	\/ 40 m\/	25°C		49°		
φm		$f = B_1,$ $C_1 = 20 pF,$	V _I = 10 mV, See Figure 100	−55°C		52°		
		-L P.,		125°C		44°		



TYPICAL CHARACTERISTICS (HIGH-BIAS MODE)

Table of Graphs

			FIGURE
۷ _{IO}	Input offset voltage	Distribution	2, 3
αVIO	Temperature coefficient	Distribution	4, 5
Vон	High-level output voltage	vs High-level output current vs Supply voltage vs Free-air temperature	6, 7 8 9
VOL	Low-level output voltage	vs Common-mode input voltage vs Differential input voltage vs Free-air temperature vs Low-level output current	10, 11 12 13 14, 15
A _{VD}	Large-signal differential voltage amplification	vs Supply voltage vs Free-air temperature vs Frequency	16 17 28, 29
I _{IB}	Input bias current	vs Free-air temperature	18
lio	Input offset current	vs Free-air temperature	18
VIС	Common-mode input voltage	vs Supply voltage	19
IDD	Supply current	vs Supply voltage vs Free-air temperature	20 21
SR	Slew rate	vs Supply voltage vs Free-air temperature	22 23
	Bias-select current	vs Supply voltage	24
V _{O(PP)}	Maximum peak-to-peak output voltage	vs Frequency	25
B ₁	Unity-gain bandwidth	vs Free-air temperature vs Supply voltage	26 27
AVD	Large-signal differential voltage amplification	vs Frequency	28, 29
φm	Phase margin	vs Supply voltage vs Free-air temperature vs Capacitive load	30 31 32
٧n	Equivalent input noise voltage	vs Frequency	33
	Phase shift	vs Frequency	28, 29



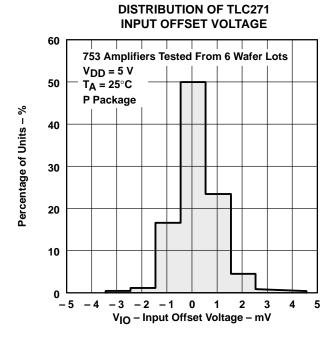
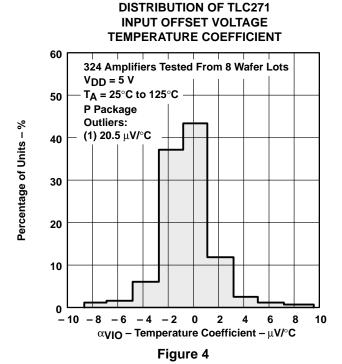


Figure 2



DISTRIBUTION OF TLC271 INPUT OFFSET VOLTAGE

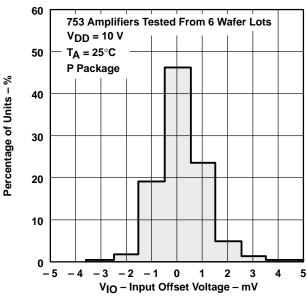
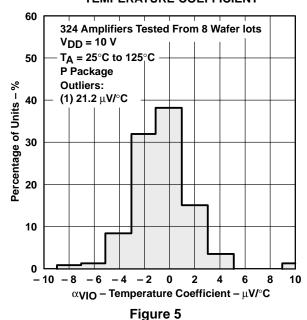


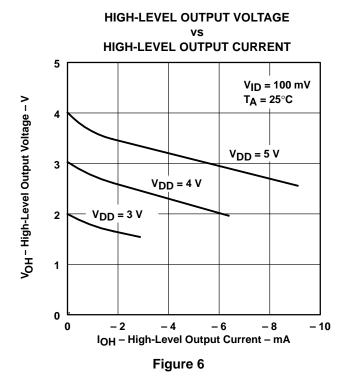
Figure 3

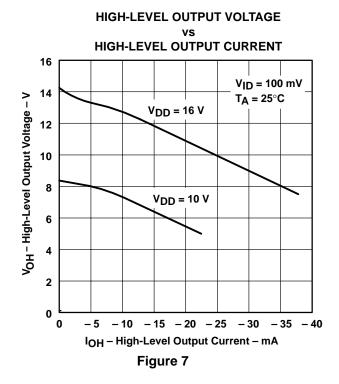
DISTRIBUTION OF TLC271 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.







HIGH-LEVEL OUTPUT VOLTAGE vs SUPPLY VOLTAGE

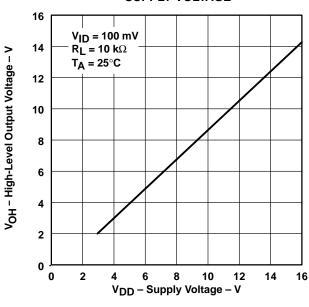
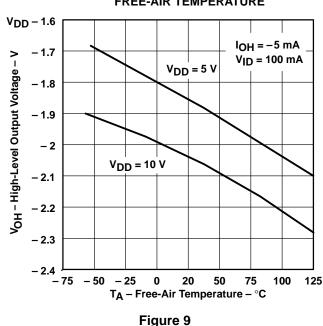


Figure 8

HIGH-LEVEL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE



† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



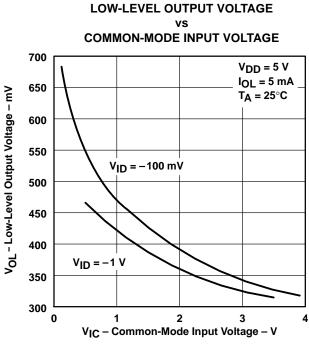
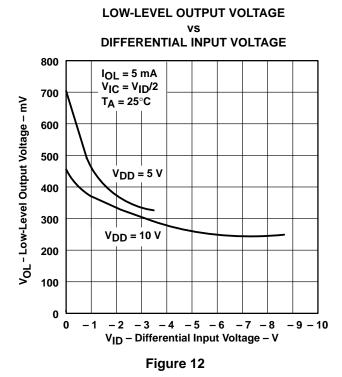


Figure 10



LOW-LEVEL OUTPUT VOLTAGE
vs
COMMON-MODE INPUT VOLTAGE

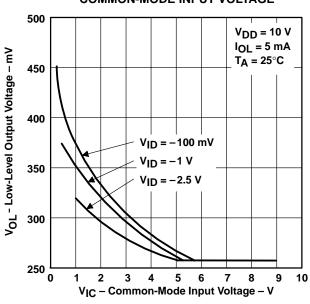


Figure 11

LOW-LEVEL OUTPUT VOLTAGE vs

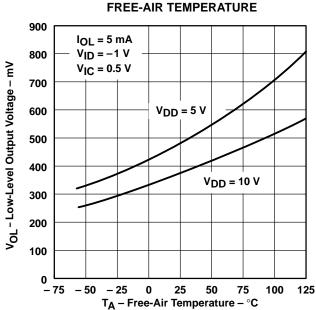


Figure 13

[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



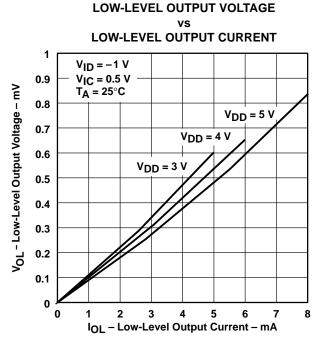
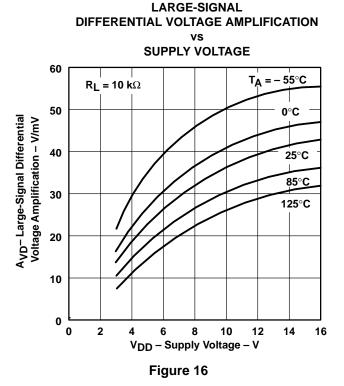


Figure 14



LOW-LEVEL OUTPUT VOLTAGE vs
LOW-LEVEL OUTPUT CURRENT

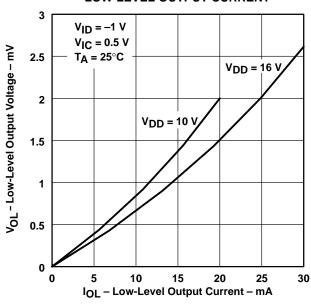


Figure 15

LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION vs

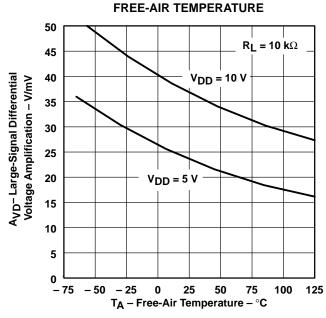


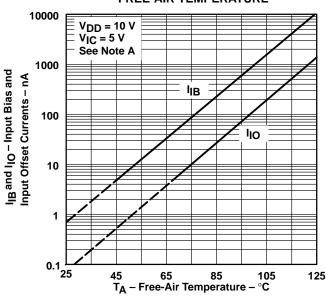
Figure 17

[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



INPUT BIAS CURRENT AND INPUT OFFSET CURRENT

FREE-AIR TEMPERATURE



NOTE A: The typical values of input bias current and input offset current below 5 pA were determined mathematically.

Figure 18

COMMON-MODE INPUT VOLTAGE (POSITIVE LIMIT)

SUPPLY VOLTAGE

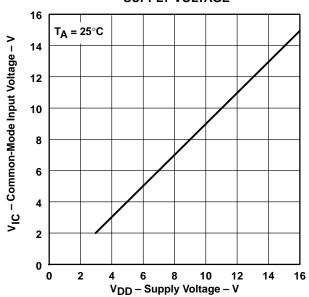


Figure 19

SUPPLY CURRENT

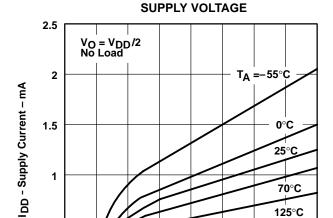


Figure 20

V_{DD} - Supply Voltage - V

6

10

12

14

0.5

0

0

2

SUPPLY CURRENT vs

FREE-AIR TEMPERATURE

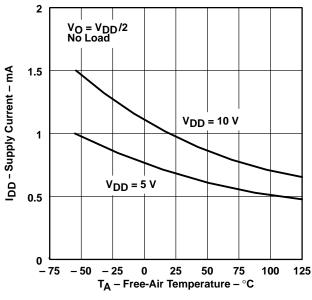
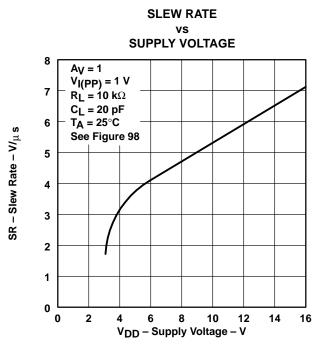


Figure 21

† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

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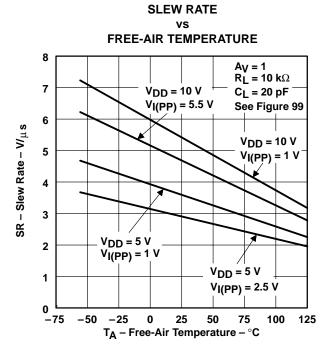
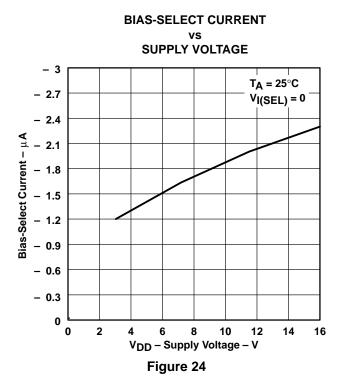
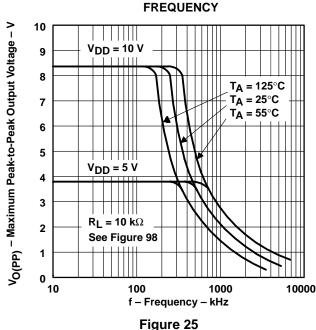


Figure 23

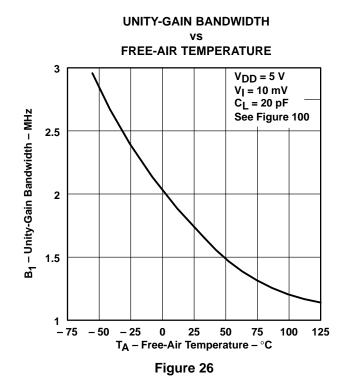


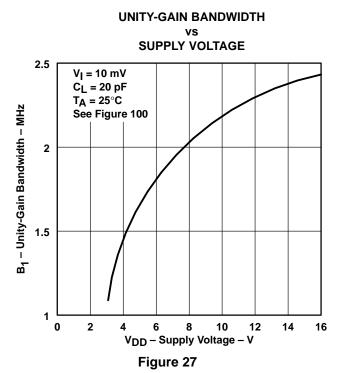




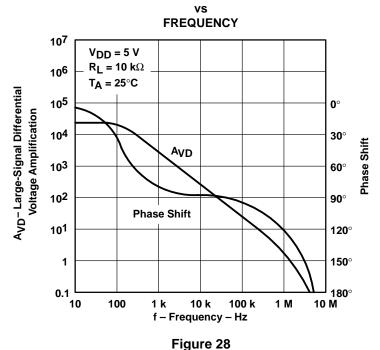
[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.







LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT



[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



LARGE-SCALE DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

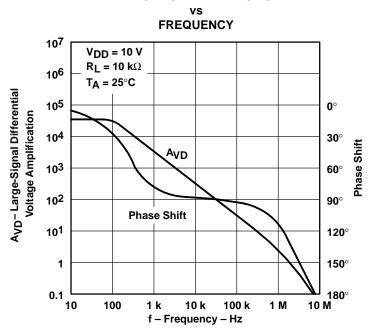
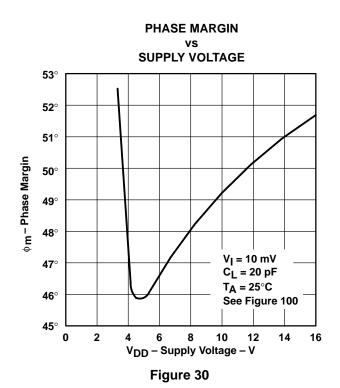
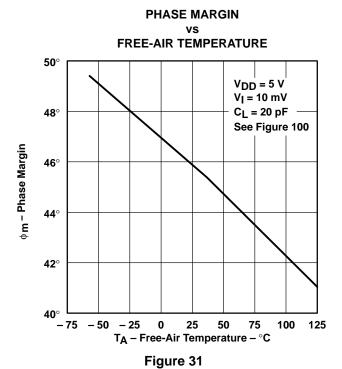


Figure 29

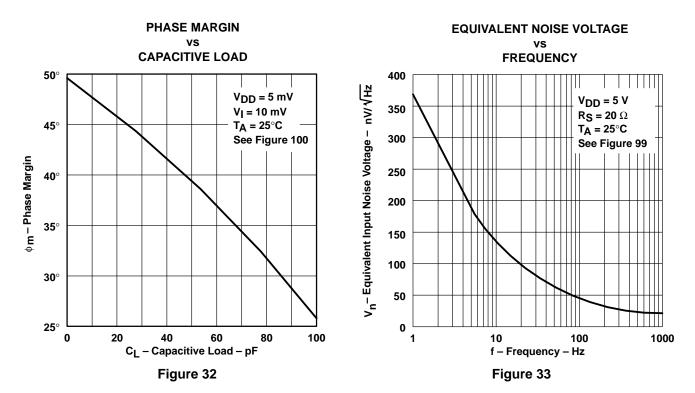




† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



TYPICAL CHARACTERISTICS (HIGH-BIAS MODE)†



† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

electrical characteristics at specified free-air temperature (unless otherwise noted)

					Т	LC271C	, TLC27	1AC, TL			
	PARAMETER		TEST CONDITIONS	T _A †	V	DD = 5 \	<i>'</i>	۷	OD = 10	V	UNIT
					MIN	TYP	MAX	MIN	TYP	MAX	
		TI C271C		25°C		1.1	10		1.1	10	
		TLC271C	V _O = 1.4 V,	Full range			12			12	
V/	land affect wells as	TI 0074 A 0	V _{IC} = 0	25°C		0.9	5		0.9	5	\/
VIO	Input offset voltage	TLC271AC	$R_S = 50 \Omega$,	Full range			6.5			6.5	mV
		TLC271BC	$R_{\parallel} = 100 \text{ k}\Omega$	25°C		0.25	2		0.26	2	
		ILC2/ IBC		Full range			3			3	
αΛΙΟ	Average temperature of input offset voltage			25°C to 70°C		1.7			2.1		μV/°C
1	Innut offeet ourrent (ooo Noto 4\	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	- A
IO	Input offset current (see Note 4)	$V_{IC} = V_{DD}/2$	70°C		7	300		7	300	pΑ
1	Innut higg gurrent (a	oo Noto 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	- A
lΒ	Input bias current (s	ee Note 4)	$V_{IC} = V_{DD}/2$	70°C		40	600		50	600	pΑ
					-0.2	-0.3		-0.2	-0.3		
				25°C	to	to		to	to		V
VICR	Common-mode inpu				4	4.2		9	9.2		
	voltage range (see Note 5)			Full range	-0.2 to			-0.2 to			V
				ruii range	3.5			8.5			V
				25°C	3.2	3.9		8	8.7		
Vон	High-level output vo	ltage	$V_{ID} = 100 \text{ mV},$	0°C	3	3.9		7.8	8.7		V
.	$R_L = 100 \text{ k}\Omega$	RL = 100 KΩ	70°C	3	4		7.8	8.7			
				25°C		0	50		0	50	
VOL	Low-level output vol	tage	$V_{ID} = -100 \text{ mV},$	0°C		0	50	-	0	50	mV
			IOT = 0	70°C		0	50		0	50	
				25°C	25	170		25	275		
A_{VD}	Large-signal differer voltage amplification		R_L = 100 kΩ, See Note 6	0°C	15	200		15	320		V/mV
	voltage amplification	l	See Note 0	70°C	15	140		15	230		
				25°C	65	91		65	94		
CMRR	Common-mode reje	ction ratio	V _{IC} = V _{ICR} min	0°C	60	91		60	94		dB
				70°C	60	92		60	94		
				25°C	70	93		70	93		
ksvr	Supply-voltage reject (ΔV _{DD} /ΔV _{IO})	tion ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V}$ $V_{O} = 1.4 \text{ V}$	0°C	60	92		60	92		dB
	(AADD/AAIO)		VU = 1.4 V	70°C	60	94		60	94		
I _I (SEL)	Input current (BIAS	SELECT)	$V_{I(SEL)} = V_{DD}/2$	25°C		-130			-160		nA
			$V_O = V_{DD}/2$,	25°C		105	280		143	300	
I_{DD}	Supply current		$V_{IC} = V_{DD}/2$,	0°C		125	320		173	400	μΑ
			No load	70°C		85	220		110	280	

[†] Full range is 0°C to 70°C.

- 5. This range also applies to each input individually.
- 6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 10 \text{ V}$, $V_{O} = 1 \text{ V}$ to 6 V.



electrical characteristics at specified free-air temperature (unless otherwise noted)

			TEST i			TLC271	I, TLC27	1AI, TLO	C271BI		
	PARAMETER		CONDITIONS	T _A †	V	_{DD} = 5 \	/	٧ _[OD = 10	٧	UNIT
			CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
		TLC2711		25°C		1.1	10		1.1	10	
		TLC2/11	V _O = 1.4 V,	Full range			13			13	
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	lanut affaat valtana	TLC271AI	V _{IC} = 0 V,	25°C		0.9	5		0.9	5	\/
VIO	Input offset voltage	TLC2/TAI	$R_S = 50 \Omega$,	Full range			7			7	mV
		TLC271BI	$R_L = 100 \text{ k}\Omega$	25°C		0.25	2		0.26	2	
		TLG27 IBI		Full range			3.5			3.5	
ανιο	Average temperature of input offset voltage	coefficient		25°C to 85°C		1.7			2.1		μV/°C
lia.	Input offset current (se	no Noto 4)	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	pА
lio	input onset current (so	se Note 4)	$V_{IC} = V_{DD}/2$	85°C		24	1000		26	1000	PΑ
1.5	Input bigg gurrent (gg	Note 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	n /
ΙΒ	Input bias current (see	e Note 4)	$V_{IC} = V_{DD}/2$	85°C		200	2000		220	2000	pА
					-0.2	-0.3		-0.2	-0.3		
				25°C	to	to 4.2		to	to 9.2		V
VICR	Common-mode input	nto 5)			4	4.2		9	9.2		
	voltage range (see Note 5)			Full range	-0.2 to			-0.2 to			V
					3.5			8.5			
				25°C	3.2	3.9		8	8.7		
VOH	High-level output volta	age	$V_{ID} = 100 \text{ mV},$ $R_{L} = 100 \text{ k}\Omega$	-40°C	3	3.9		7.8	8.7		V
			K[= 100 K22	85°C	3	4		7.8	8.7		
				25°C		0	50		0	50	
VOL	Low-level output volta	ge	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 0$	-40°C		0	50		0	50	mV
			I OL = 0	85°C		0	50		0	50	
				25°C	25	170		25	275		
A_{VD}	Large-signal differenti voltage amplification	al	R_L = 100 kΩ, See Note 6	-40°C	15	270		15	390		V/mV
	voltage amplification		See Note o	85°C	15	130		15	220		
				25°C	65	91		65	94		
CMRR	Common-mode reject	ion ratio	V _{IC} = V _{ICR} min	-40°C	60	90		60	93		dB
				85°C	60	90		60	94		
			.,	25°C	70	93		70	93		
ksvr	Supply-voltage rejecti (ΔV _{DD} /ΔV _{IO})	on ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V}$ $V_{O} = 1.4 \text{ V}$	-40°C	60	91		60	91		dB
	(A 1 DD / A 1 D)		.0 = •	85°C	60	94		60	94		
I _(SEL)	Input current (BIAS SI	ELECT)	$V_{I(SEL)} = V_{DD}/2$	25°C		-130			-160		nA
			$V_O = V_{DD}/2$,	25°C		105	280		143	300	
I _{DD}	Supply current		$V_{IC} = V_{DD}/2$,	-40°C		158	400		225	450	μΑ
			No load	85°C		80	200		103	260	

[†]Full range is –40°C to 85°C.

- 5. This range also applies to each input individually.
- 6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 10 \text{ V}$, $V_{O} = 1 \text{ V}$ to 6 V.



electrical characteristics at specified free-air temperature (unless otherwise noted)

						TLC2	71M			
	PARAMETER	TEST CONDITIONS	T _A †	V	DD = 5 \	<i>'</i>	٧ _C	D = 10	٧	UNIT
		CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
Vio	Input offset voltage	V _O = 1.4 V, V _{IC} = 0 V,	25°C		1.1	10		1.1	10	mV
VIO	input onset voltage	$R_S = 50 \Omega$, $R_L = 100 k\Omega$	Full range			12			12	
ανιο	Average temperature coefficient of input offset voltage		25°C to 125°C		1.7			2.1		μV/°C
li o	Input offset current (see Note 4)	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	pА
ΙΟ	input onset current (see Note 4)	$V_{IC} = V_{DD}/2$	125°C		1.4	15		1.8	15	nA
lin	Input bias current (see Note 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	pА
ΙВ	input bias current (see Note 4)	$V_{IC} = V_{DD}/2$	125°C		9	35		10	35	nA
V	Common-mode input		25°C	0 to 4	-0.3 to 4.2		0 to 9	-0.3 to 9.2		V
VICR	voltage range (see Note 5)		Full range	0 to 3.5			0 to 8.5			V
			25°C	3.2	3.9		8	8.7		
Vон	High-level output voltage	$V_{ID} = 100 \text{ mV},$ $R_L = 100 \text{ k}\Omega$	−55°C	3	3.9		7.8	8.6		V
		KL = 100 K22	125°C	3	4		7.8	8.6		
			25°C		0	50		0	50	
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 0$	−55°C		0	50		0	50	mV
		IOL = 0	125°C		0	50		0	50	
			25°C	25	170		25	275		
AVD	Large-signal differential voltage amplification	R_L = 10 kΩ See Note 6	−55°C	15	290		15	420		V/mV
	voltage amplification	000140100	125°C	15	120		15	190		
			25°C	65	91		65	94		
CMRR	Common-mode rejection ratio	V _{IC} = V _{ICR} min	−55°C	60	89		60	93		dB
			125°C	60	91		60	93		
			25°C	70	93		70	93		
k _{SVR}	Supply-voltage rejection ratio (ΔV _{DD} /ΔV _{IO})	$V_{DD} = 5 \text{ V to } 10 \text{ V}$ $V_{O} = 1.4 \text{ V}$	−55°C	60	91		60	91		dB
	(A * UU/ A * IU/		125°C	60	94		60	94		
I _{I(SEL)}	Input current (BIAS SELECT)	$V_{I(SEL)} = V_{DD}/2$	25°C		-130			-160		nA
		$V_O = V_{DD}/2$,	25°C		105	280		143	300	
I_{DD}	Supply current	$V_{IC} = V_{DD}/2$,	−55°C		170	440		245	500	μΑ
		No load	125°C		70	180		90	240	

[†]Full range is -55°C to 125°C.

- 5. This range also applies to each input individually.
- 6. At V_{DD} = 5 V, V_{O} = 0.25 V to 2 V; at V_{DD} = 10 V, V_{O} = 1 V to 6 V.



operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	PARAMETER	TEST CO	NDITIONS	TA	TLC271C, TLC271AC, TLC271BC			UNIT	
					MIN	TYP	MAX		
				25°C		0.43			
			V _{I(PP)} = 1 V	0°C		0.46			
SR	Slow rate of unity gain	$R_L = 100 \text{ k}\Omega$, $C_L = 20 \text{ pF}$,		70°C		0.36		\//uo	
J SK	Slew rate at unity gain	See Figure 98		25°C		0.40		V/μs	
			$V_{I(PP)} = 2.5 V$	0°C		0.43			
			70°C		0.34				
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz	
				25°C		55			
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_I = 100 \text{ k}\Omega$,		C _L = 20 pF, See Figure 98	0°C		60		kHz
			Gee i igure 90	70°C		50			
		.,		25°C		525			
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF,$	0°C		600		kHz	
.		See rigule 100		70°C		400			
		V 40 mV	4 D	25°C		40°			
φm	Phase margin C	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ , See Figure 100	0°C		41°			
		20 pr,	200guro 100	70°C		39°			

	PARAMETER	TEST CO	NDITIONS	TA	TLC271 TL	UNIT			
					MIN	TYP	MAX		
				25°C		0.62			
			V _{I(PP)} = 1 V	0°C		0.67			
SR	Clausesta at units main	$R_L = 100 \text{ k}\Omega$		70°C		0.51		\//v.a	
J SK	Slew rate at unity gain	C _L = 20 pF, See Figure 98		25°C		0.56		V/μs	
				V _{I(PP)} = 5.5 V	0°C		0.61	61 96 32	
				70°C		0.46			
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz	
			_	25°C		35			
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_I = 100 \text{ k}\Omega$,	C _L = 20 pF,	0°C		40		kHz	
			See Figure 30	70°C		30			
		.,,		25°C		635			
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	0°C		710		kHz	
		See rigure 100		70°C		510			
		\(\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	4 D	25°C		43°			
φm		$V_{\parallel} = 10 \text{ mV},$ $C_{\parallel} = 20 \text{ pF},$	f = B ₁ , See Figure 100	0°C		44°			
		20 20 pri,	232garo 100	70°C		42°			

operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	PARAMETER	TEST CO	TEST CONDITIONS			TLC271I, TLC271AI, TLC271BI		
				TA	MIN	TYP	MAX	
				25°C		0.43		
			V _{I(PP)} = 1 V	-40°C		0.51		
SR	Class rate at units agin	$R_L = 100 \text{ k}\Omega$, $C_L = 20 \text{ pF}$,		85°C		0.35		1////
SK	Slew rate at unity gain	See Figure 98		25°C		0.40		V/μs
			V _{I(PP)} = 2.5 V	−40°C		0.48		
				85°C		0.32		
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz
				25°C		55		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_I = 100 \text{ k}\Omega$,	C _L = 20 pF, See Figure 98	-40°C		75		kHz
		K_ = 100 KS2,	See Figure 90	85°C		45		
				25°C		525		
В1	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	-40°C		770		MHz
- 1		See Figure 100		85°C		370		
φm		V 40V	, p	25°C		40°		
		$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ , See Figure 100	-40°C		43°		
		John See Figure 100		85°C		38°		

	PARAMETER	TEST CO	TA	TLC271	UNIT				
					MIN	TYP	MAX		
				25°C		0.62			
			V _{I(PP)} = 1 V	−40°C		0.77			
SR	Claus rate at units rain	1	2,	85°C		0.47		1////	
J SK	Slew rate at unity gain			25°C		0.56		V/μs	
			V _{I(PP)} = 5.5 V	-40°C		0.70			
				85°C		0.44			
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz	
				25°C		35			
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$,3 $R_L = 100 \text{ k}\Omega$,	C _L = 20 pF,	C _L = 20 pF,	-40°C		45		kHz
			See Figure 30	85°C		25			
				25°C		635			
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	-40°C		880		kHz	
		See Figure 100		85°C		480			
		V 40 == V	4 D	25°C		43°			
φm		$V_{\parallel} = 10 \text{ mV},$ $C_{\perp} = 20 \text{ pF},$	f = B ₁ , See Figure 100	-40°C		46°			
TIII		0L = 20 pr ,	223119410100	85°C		41°			



operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

DADAMETER		TEST CONDITIONS		_	TLC271M			
	PARAMETER	l lesi cc	SNOTHUNS	TA	MIN	TYP	MAX	UNIT
SR	Slew rate at unity gain	$R_L = 100 \text{ k}\Omega$, $C_L = 20 \text{ pF}$, See Figure 98	V _{I(PP)} = 1 V	25°C		0.43		V/μs
				−55°C		0.54		
				125°C		0.29		
			V _{I(PP)} = 2.5 V	25°C		0.40		
				−55°C		0.50		
				125°C		0.28		
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz
	Maximum output-swing bandwidth	$V_O = V_{OH},$ $R_L = 100 \text{ k}\Omega,$	C _L = 20 pF, See Figure 98	25°C		55		kHz
ВОМ				−55°C		80		
				125°C		40		
	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	C _L = 20 pF,	25°C		525		kHz
B ₁				−55°C		850		
				125°C		330		
	Phase margin	V _I = 10 mV, C _L = 20 pF,	f = B ₁ , See Figure 100	25°C		40°		
фm				−55°C		43°		
				125°C		36°		

DADAMETED		TEST CONDITIONS		т.	TLC271M			
	PARAMETER	TEST CC	SNOTTIONS	TA	MIN	TYP	MAX	UNIT
SR	Slew rate at unity gain	$R_L = 100 \text{ k}\Omega$, $C_L = 20 \text{ pF}$, See Figure 98	V _{I(PP)} = 1 V	25°C		0.62		V/μs
				−55°C		0.81		
				125°C		0.38		
			V _{I(PP)} = 5.5 V	25°C		0.56		
				−55°C		0.73		
				125°C		0.35		
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		32		nV/√ Hz
	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 100 \text{ k}\Omega$,	C _L = 20 pF, See Figure 98	25°C		35		kHz
ВОМ				−55°C		50		
				125°C		20		
	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	C _L = 20 pF,	25°C		635		kHz
В1				−55°C		960		
				125°C		440		
	Phase margin	V _I = 10 mV, C _L = 20 pF,		25°C		43°		
φm				−55°C		47°		
				125°C		39°		

Table of Graphs

			FIGURE
۷ _{IO}	Input offset voltage	Distribution	34, 35
αVIO	Temperature coefficient	Distribution	36, 37
Vон	High-level output voltage	vs High-level output current vs Supply voltage vs Free-air temperature	38, 39 40 41
VOL	Low-level output voltage	vs Common-mode input voltage vs Differential input voltage vs Free-air temperature vs Low-level output current	42, 43 44 45 46, 47
AVD	Large-signal differential voltage amplification	vs Supply voltage vs Free-air temperature vs Frequency	48 49 60, 61
I _{IB}	Input bias current	vs Free-air temperature	50
lio	Input offset current	vs Free-air temperature	50
VI	Maximum Input voltage	vs Supply voltage	51
IDD	Supply current	vs Supply voltage vs Free-air temperature	52 53
SR	Slew rate	vs Supply voltage vs Free-air temperature	54 55
	Bias-select current	vs Supply voltage	56
V _{O(PP)}	Maximum peak-to-peak output voltage	vs Frequency	57
B ₁	Unity-gain bandwidth	vs Free-air temperature vs Supply voltage	58 59
φm	Phase margin	vs Supply voltage vs Free-air temperature vs Capacitive load	62 63 64
٧n	Equivalent input noise voltage	vs Frequency	65
	Phase shift	vs Frequency	60, 61



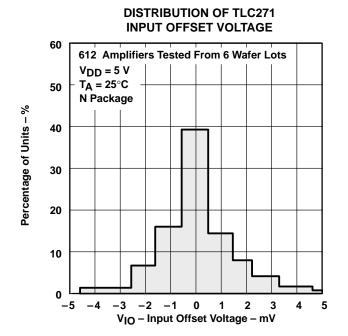
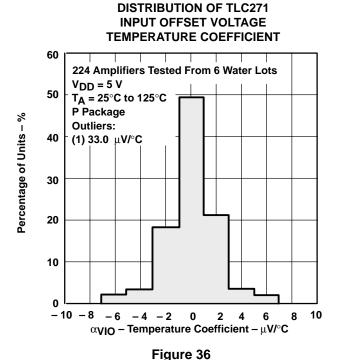


Figure 34



DISTRIBUTION OF TLC271 INPUT OFFSET VOLTAGE

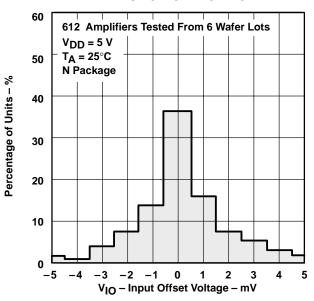


Figure 35

DISTRIBUTION OF TLC271 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT

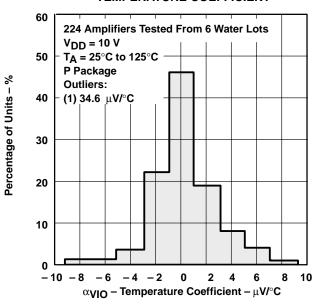
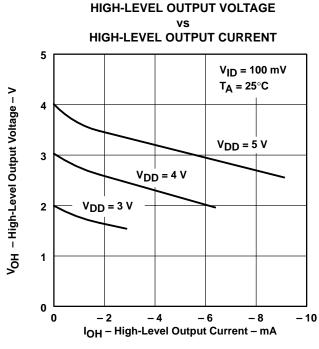


Figure 37

[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.





HIGH-LEVEL OUTPUT CURRENT

16

V_{ID} = 100 mV

T_A = 25°C

V_{DD} = 16 V

V_{DD} = 10 V

10

V_{DD} = 10 V

10

0

-5

-10

-15

-20

-25

-30

-35

-40

HIGH-LEVEL OUTPUT VOLTAGE

Figure 38





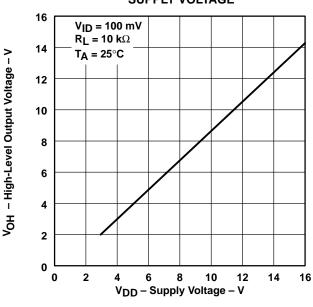
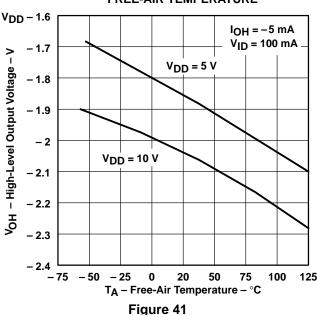


Figure 40

HIGH-LEVEL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE

IOH - High-Level Output Current - mA



[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



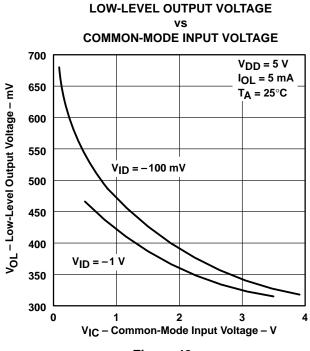


Figure 42

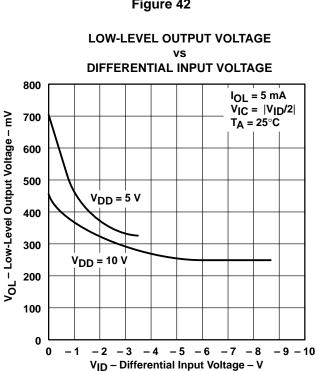


Figure 44

LOW-LEVEL OUTPUT VOLTAGE COMMON-MODE INPUT VOLTAGE

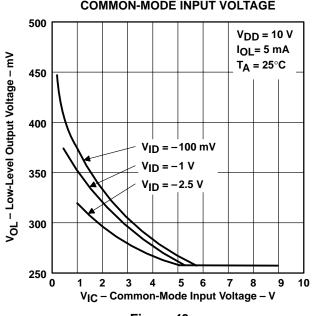
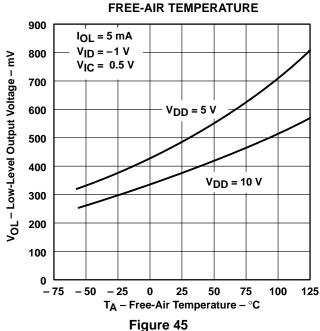


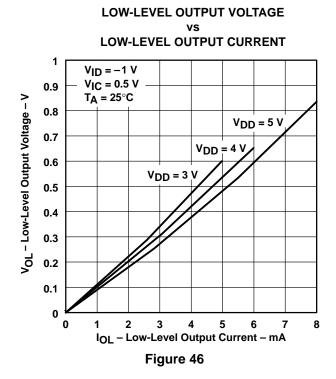
Figure 43

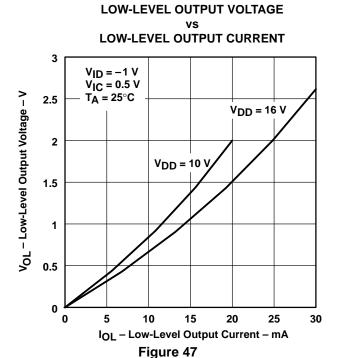
LOW-LEVEL OUTPUT VOLTAGE



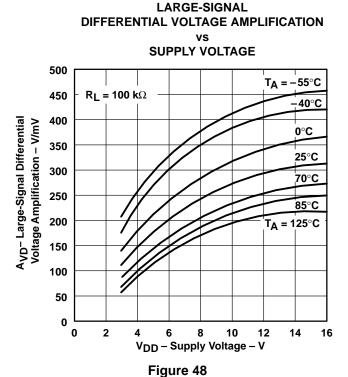
[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

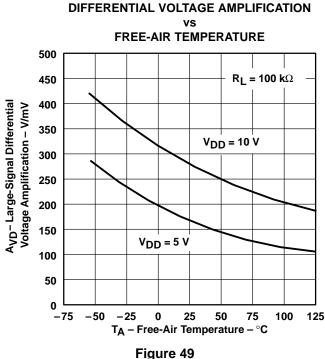






LARGE-SIGNAL



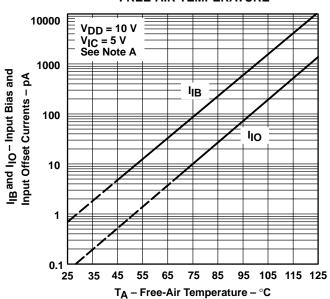


[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



INPUT BIAS CURRENT AND INPUT OFFSET CURRENT





NOTE A: The typical values of input bias current and input offset current below 5 pA were determined mathematically.

Figure 50

SUPPLY CURRENT vs SUPPLY VOLTAGE

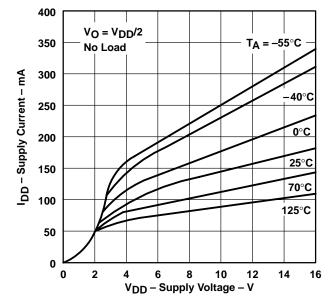


Figure 52

MAXIMUM INPUT VOLTAGE

SUPPLY VOLTAGE

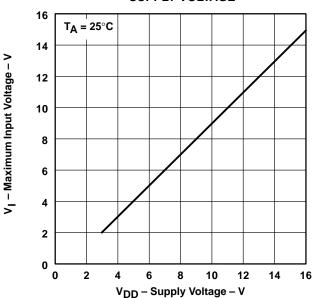
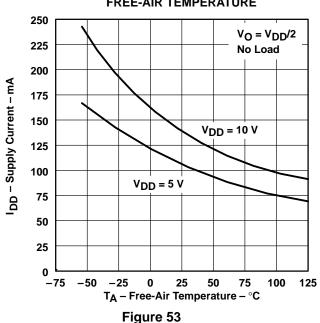


Figure 51

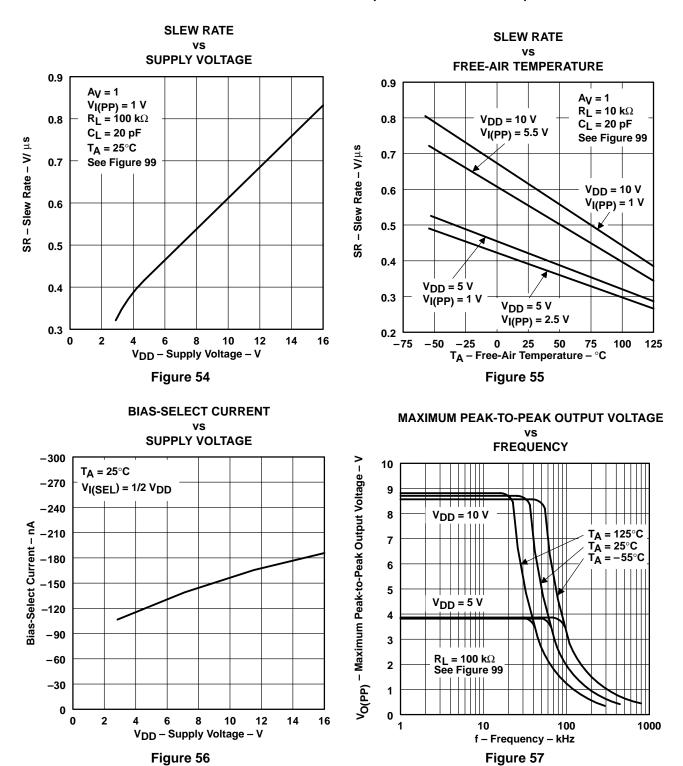
SUPPLY CURRENT





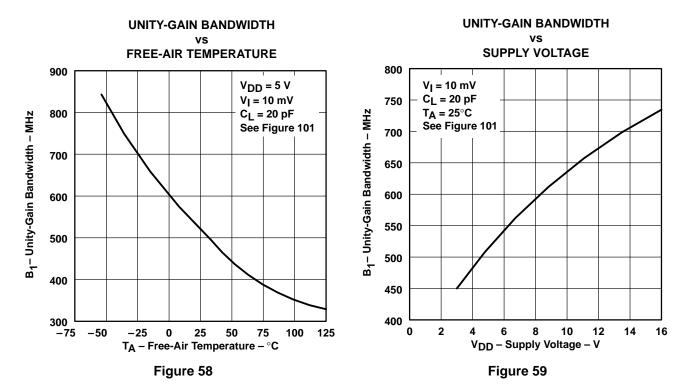
† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



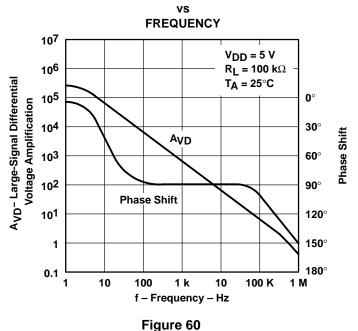


[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.





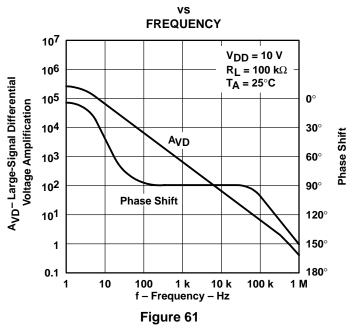
LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

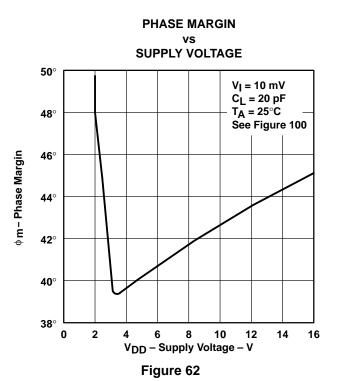


[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

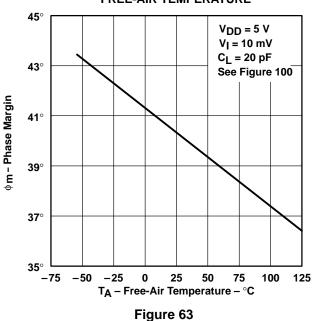


LARGE-SIGNAL DIFFERENTIAL VOLTAGE **AMPLIFICATION AND PHASE SHIFT**





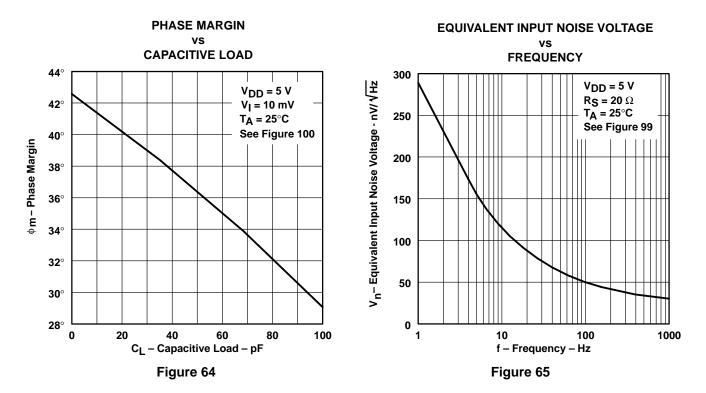
PHASE MARGIN vs FREE-AIR TEMPERATURE



† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



TYPICAL CHARACTERISTICS (MEDIUM-BIAS MODE)†



† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

electrical characteristics at specified free-air temperature (unless otherwise noted)

					Т	LC2710	, TLC27	1AC, TL	C271BC	;	
	PARAMETER		TEST CONDITIONS	T _A †	V	DD = 5 \	/	۷ _l	_{DD} = 10	V	UNIT
			CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
		TI C074C		25°C		1.1	10		1.1	10	
		TLC271C	V _O = 1.4 V,	Full range			12			12	
1/1.5	lanut offeet valtere	TLC271AC	V _{IC} = 0 V,	25°C		0.9	5		0.9	5	m)/
VIO	Input offset voltage	TLC2/TAC	$R_S = 50 \Omega$,	Full range			6.5			6.5	mV
		TLC271BC	$R_{I} = 1 M\Omega$	25°C		0.24	2		0.26	2	
		TLCZITBC		Full range			3			3	
ανιο	Average temperature of input offset voltage	oefficient of		25°C to 70°C		1.1			1		μV/°C
li o	Input offect current (co	o Noto 4)	$V_O = V_{DD}/2$	25°C		0.1	60		0.1	60	nΛ
lio	Input offset current (se	e Note 4)	$V_{IC} = V_{DD}/2$	70°C		7	300		8	300	pА
1.5	Input bigg gurrent (ago	Note 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	5 A
ΙΒ	Input bias current (see	Note 4)	$V_{IC} = V_{DD}/2$	70°C		40	600		50	600	pА
					-0.2	-0.3		-0.2	-0.3		
				25°C	to 4	to 4.2		to 9	to 9.2		V
VICR	Common-mode input voltage range (see Not	e 5)			-0.2	4.2		-0.2	9.2		
	voltage range (see Note 3)			Full range	-0.2 to			-0.2 to			V
					3.5			8.5			
				25°C	3.2	4.1		8	8.9		
Vон	High-level output voltage	ge	V_{ID} = 100 mV, R _L = 1 M Ω	0°C	3	4.1		7.8	8.9		V
			11/2 1 1/122	70°C	3	4.2		7.8	8.9		
			., ,,	25°C		0	50		0	50	
VOL	Low-level output voltag	je	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 0$	0°C		0	50		0	50	mV
			IOL = 0	70°C		0	50		0	50	
			5 4140	25°C	50	520		50	870		
A_{VD}	Large-signal differentia voltage amplification	l	$R_L = 1 M\Omega$, See Note 6	0°C	50	700		50	1030		V/mV
	voltago amplinoation		000 11010 0	70°C	50	380		50	660		
				25°C	65	94		65	97		
CMRR	Common-mode rejection	on ratio	V _{IC} = V _{ICR} min	0°C	60	95		60	97		dB
				70°C	60	95		60	97		
	0 1 1: :		.,	25°C	70	97		70	97		
ksvr	Supply-voltage rejectio (ΔV _{DD} /ΔV _{IO})	n ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V}$ $V_{O} = 1.4 \text{ V}$	0°C	60	97		60	97		dB
	(A * DD/A * IO/		VO = 1.5 V	70°C	60	98		60	98		
I _{I(SEL)}	Input current (BIAS SE	LECT)	V _{I(SEL)} = V _{DD}	25°C		65			95		nA
			$V_O = V_{DD}/2$,	25°C		10	17		14	23	
I _{DD}	Supply current		$V_{IC} = V_{DD}/2$,	0°C		12	21		18	33	μΑ
			No load	70°C		8	14		11	20	

[†] Full range is 0°C to 70°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.

^{6.} At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 10 \text{ V}$, $V_{O} = 1 \text{ V}$ to 6 V.



^{5.} This range also applies to each input individually.

electrical characteristics at specified free-air temperature (unless otherwise noted)

	TLC271I, TLC271AI, TLC271BI										
	PARAMETER		TEST CONDITIONS	T _A †	V	DD = 5 \	/	V	DD = 10	٧	UNIT
			CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
		TLC2711		25°C		1.1	10		1.1	10	
		ILC2/11	V _O = 1.4 V,	Full range			13			13	
\ \ \ -	land offert colleges	TI C074 A I	$V_{IC} = 0 V$	25°C		0.9	5		0.9	5	\/
VIO	Input offset voltage	TLC271AI	$R_S = 50 \Omega$,	Full range			7			7	mV
		TLC271BI	$R_L = 1 M\Omega$	25°C		0.24	2		0.26	2	
		TLC27 IBI		Full range			3.5			3.5	
ανιο	Average temperature of input offset voltage			25°C to 85°C		1.1			1		μV/°C
	land effect compact /s	Not 4\	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	^
ΙO	Input offset current (s	see Note 4)	$V_{IC} = V_{DD}/2$	85°C		24	1000		26	1000	pΑ
1	land bing summed (as	a Nata 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	A
IB	Input bias current (se	ee Note 4)	$V_{IC} = V_{DD}/2$	85°C		200	2000		220	2000	pΑ
					-0.2	-0.3		-0.2	-0.3		
				25°C	to 4	to		to 9	to 9.2		V
VICR	Common-mode input voltage range (see N					4.2			9.2		
	voltage range (see iv	ole 3)		Full range	-0.2 to			-0.2 to			V
					3.5			8.5			
				25°C	3 4.1 8 8		8.9				
Vон	High-level output volt	tage	$V_{ID} = 100 \text{ mV},$ $R_{L} = 1 \text{ M}\Omega$	-40°C	3	4.1		7.8	8.9		V
			1112	85°C	3	4.2		7.8	8.9		
				25°C		0	50		0	50	
VOL	Low-level output volta	age	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 0$	-40°C		0	50		0	50	mV
			IOL = 0	85°C		0	50		0	50	
				25°C	50	520		50	870		
AVD	Large-signal different voltage amplification	tial	R_L = 1 MΩ See Note 6	−40°C	50	900		50	1550		V/mV
	voltage amplification		OCC NOIC O	85°C	50	330		50	585		
				25°C	65	94		65	97		
CMRR	Common-mode rejec	tion ratio	V _{IC} = V _{ICR} min	-40°C	60	95		60	97		dB
				85°C	60	95		60	98		
				25°C	70	97		70	97		
ksvr	Supply-voltage reject (ΔV _{DD} /ΔV _{IO})	tion ratio	V _{DD} = 5 V to 10 V V _O = 1.4 V	-40°C	60	97		60	97		dB
	(¬^DD/¬^IO)		VU = 1.4 V	85°C	60	98		60	98		
I _{I(SEL)}	Input current (BIAS S	SELECT)	V _{I(SEL)} = V _{DD}	25°C		65			95		nA
			$V_O = V_{DD}/2$,	25°C		10	17		14	23	
I _{DD}	Supply current		$V_{IC} = V_{DD}/2$,	-40°C		16	27		25	43	μΑ
			No load	85°C		17	13		10	18	

[†] Full range is –40 to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.

- 5. This range also applies to each input individually.
- 6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 10 \text{ V}$, $V_{O} = 1 \text{ V}$ to 6 V.



electrical characteristics at specified free-air temperature (unless otherwise noted)

		TEOT				TLC2	71M			
	PARAMETER	TEST CONDITIONS	T _A †	V	DD = 5 \	/	٧ _[_{DD} = 10	V	UNIT
		CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	
VIO	Input offset voltage	V _O = 1.4 V, V _{IC} = 0 V,	25°C		1.1	10		1.1	10	mV
V10	input onset voltage	$R_S = 50 \Omega$, $R_L = 1 M\Omega$	Full range			12			12	IIIV
αVIO	Average temperature coefficient of input offset voltage		25°C to 125°C		1.4			1.4		μV/°C
1.0	Input offset current (see Note 4)	$V_O = V_{DD}/2$,	25°C		0.1	60		0.1	60	pА
liO	input onset current (see Note 4)	$V_{IC} = V_{DD}/2$	125°C		1.4	15		1.8	15	nA
1	Input him ourrent (and Note 4)	$V_O = V_{DD}/2$,	25°C		0.6	60		0.7	60	pА
lΒ	Input bias current (see Note 4)	$V_{IC} = V_{DD}/2$	125°C		9	35		10	35	nA
	Common-mode input		25°C	0 to 4	-0.3 to 4.2		0 to 9	-0.3 to 9.2		V
VICR	voltage range (see Note 5)		Full range	0 to 3.5			0 to 8.5			V
			25°C	3.2	4.1		8	8.9		
VOH	High-level output voltage	$V_{ID} = 100 \text{ mV},$ $R_L = 1 \text{ M}\Omega$	−55°C	3	4.1		7.8	8.8		V
			125°C	3	4.2		7.8	9		
			25°C		0	50		0	50	
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$ $I_{OL} = 0$	−55°C		0	50		0	50	mV
		I OL - V	125°C		0	50		0	50	
			25°C	50	520		50	870		
AVD	Large-signal differential voltage amplification	R_L = 1 MΩ, See Note 6	−55°C	25	1000		25	1775		V/mV
	voltage amplification	OCC NOIC O	125°C	25	200		25	380		
			25°C	65	94		65	97		
CMRR	Common-mode rejection ratio	V _{IC} = V _{ICR} min	−55°C	60	95		60	97		dB
			125°C	60	85		60	91		
	0 1 1 1 1 1		25°C	70	97		70	97		
ksvr	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{IO})$	$V_{DD} = 5 \text{ V to } 10 \text{ V}$ $V_{O} = 1.4 \text{ V}$	−55°C	60	97		60	97		dB
	(A*UU'A*IU)	1.4 4	125°C	60	98		60	98		
I _I (SEL)	Input current (BIAS SELECT)	$V_{I(SEL)} = V_{DD}$	25°C		65			95		nA
		$V_O = V_{DD}/2$,	25°C		10	17		14	23	
I_{DD}	Supply current	$V_{IC} = V_{DD}/2$	−55°C		17	30		28	48	μΑ
		No load	125°C		7	12		9	15	

† Full range is -55°C to 125°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.

- 5. This range also applies to each input individually.
- 6. At $V_{DD} = 5 \text{ V}$, $V_{O} = 0.25 \text{ V}$ to 2 V; at $V_{DD} = 10 \text{ V}$, $V_{O} = 1 \text{ V}$ to 6 V.



operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	PARAMETER	TEST CO	ONDITIONS	TA	TLC271		UNIT	
					MIN	TYP	MAX	
				25°C		0.03		
			V _{I(PP)} = 1 V	0°C		0.04		
SR	Claus rate at units rain	$R_L = 1 M\Omega$, $C_L = 20 pF$,		70°C		0.03		\//v.a
J SK	Slew rate at unity gain	See Figure 98		25°C		0.03		V/μs
			$V_{I(PP)} = 2.5 V$	0°C		0.03		
				70°C		0.02		
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
				25°C		5		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_I = 1 M\Omega$,		0°C		6		kHz
			Gee rigure 90	70°C		4.5		
		., ., .,		25°C		85		
В1	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	0°C		100		kHz
		See rigure 100		70°C		65		
		V 40 V	4 D	25°C		34°		
φm			f = B ₁ , See Figure 100	0°C		36°		
		- 25 μι,	200garo 100	70°C		30°		

operating characteristics at specified free-air temperature, $V_{DD} = 10 \text{ V}$

	PARAMETER	TEST CO	NDITIONS	TA	TLC2710 TL		UNIT	
					MIN	TYP	MAX	
				25°C		0.05		
			V _{I(PP)} = 1 V	0°C		0.05		
SR	Clay rate at unity gain	$R_L = 1 M\Omega$, $C_L = 20 pF$,		70°C		0.04		V/μs
J SK	Slew rate at unity gain	See Figure 98		25°C		0.04		V/μS
		J	V _{I(PP)} = 5.5 V	0°C		0.05		
				70°C		0.04		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
				25°C		1		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 1 M\Omega$,	C _L = 20 pF,	0°C		1.3		kHz
		1 1 10122,	occ rigure so	70°C		0.9		
		V 40V		25°C		110		
В1	Unity-gain bandwidth		$C_L = 20 pF,$	0°C		125		kHz
		See Figure 100		70°C		90		
		V 40 V	4 D	25°C		38°		_
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ , See Figure 100	0°C		40°		
		2 2 pr,	233	70°C		34°		

operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	PARAMETER	TEST CO	NDITIONS	TA	TLC27		UNIT	
					MIN	TYP	MAX	
				25°C		0.03		
			V _{I(PP)} = 1 V	-40°C		0.04		
SR	Slow rate at unity gain	$R_L = 1 M\Omega$, $C_L = 20 pF$,		85°C		0.03		\//··-
J SK	Slew rate at unity gain	See Figure 98		25°C		0.03		V/μs
			$V_{I(PP)} = 2.5 V$	-40°C		0.04		
				85°C		0.02		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
				25°C		5		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_I = 1 M\Omega$,	C _L = 20 pF, See Figure 98	-40°C		7		kHz
			Gee rigule 90	85°C		4		
		.,,		25°C		85		
В1	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF,$	-40°C		130		MHz
		See rigule 100		85°C		55		
		V 40 mV	4 D	25°C		34°		
φm	Phase margin		f = B ₁ , See Figure 100	-40°C		38°		
		- 20 μ,	255 : .9310 100	85°C		28°	·	

operating characteristics at specified free-air temperature, $V_{DD} = 10 \text{ V}$

	PARAMETER	TEST CO	NDITIONS	TA	TLC2710 TL		UNIT	
					MIN	TYP	MAX	
				25°C		0.05		
			V _{I(PP)} = 1 V	-40°C		0.06		
SR	Slow rate at unity gain	$R_L = 1 M\Omega$, $C_L = 20 pF$,		85°C		0.03		\//uo
SK	Slew rate at unity gain	See Figure 98		25°C		0.04		V/μs
		3	V _{I(PP)} = 5.5 V	-40°C		0.05		
				85°C		0.03		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
				25°C		1		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_I = 1 M\Omega$,	C _L = 20 pF, See Figure 98	-40°C		1.4		kHz
			See rigule 30	85°C		0.8		
				25°C		110		
В1	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	-40°C		155		MHz
		See rigule 100		85°C		80		
		V 40 VI	4 D	25°C		38°		
φm	Phase margin	$V_{ } = 10 \text{ mV,I}$ $C_{ } = 20 \text{ pF,}$	f = B ₁ , See Figure 100	-40°C		42°		
		- 20 βι,		85°C		32°		



operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	DADAMETED	TEOT 00	NETIONS	T .	Т	LC271M		LIAUT
	PARAMETER	IESI CC	NDITIONS	TA	MIN	TYP	MAX	UNIT
				25°C		0.03		
			V _{I(PP)} = 1 V	−55°C		0.04		
SR	Slew rate at unity gain	$R_L = 1 M\Omega$, $C_L = 20 pF$,		125°C		0.02		V/μs
J SK	Siew rate at unity gain	See Figure 98		25°C		0.03		ν/μ5
		Ĭ	$V_{I(PP)} = 2.5 \text{ V}$	−55°C		0.04		
				125°C		0.02		
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
				25°C		5		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_I = 1 M\Omega$,	C _L = 20 pF,	−55°C		8		kHz
		1 1 10122,	Occ rigure 50	125°C		3		
		., ., .,		25°C		85		
В1	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 pF$,	−55°C		140		kHz
		Occ rigare 100		125°C		45		
		V 40 V	4 D	25°C		34°		
φm	Phase margin	$V_{ } = 10 \text{ mV},$ $C_{ } = 20 \text{ pF},$	f = B ₁ , See Figure 100	−55°C		39°		
		-L -0 p.,	g	125°C		25°		

operating characteristics at specified free-air temperature, $V_{DD} = 10 \text{ V}$

	DADAMETED	TEST CO	NDITIONS	Τ.	Т	LC271M		LINUT
	PARAMETER	TEST CC	ONDITIONS	TA	MIN	TYP	MAX	UNIT
				25°C		0.05		
			V _{I(PP)} = 1 V	−55°C		0.06		
SR	Slew rate at unity gain	$R_L = 1 M\Omega$,		125°C		0.03		\//uo
J SK	Siew rate at unity gain	C _L = 20 pF, See Figure 98		25°C		0.04		V/μs
			$V_{I(PP)} = 5.5 V$	−55°C		0.06		
				125°C		0.03		
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 99	$R_S = 20 \Omega$,	25°C		68		nV/√ Hz
				25°C		1		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$, $R_L = 1 M\Omega$,	C _L = 20 pF,	−55°C		1.5		kHz
		1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	See rigure 90	125°C		0.7		
				25°C		110		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 100	$C_L = 20 \text{ pF},$	−55°C		165		kHz
		See Figure 100		125°C		70		
		V 40 V	, ,	25°C		38°		
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{I} = 20 \text{ pF},$	f = B ₁ , See Figure 100	−55°C		43°		
		0L - 20 pr,		125°C		29°		

TYPICAL CHARACTERISTICS (LOW-BIAS MODE)

Table of Graphs

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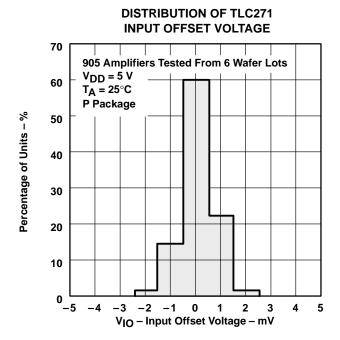
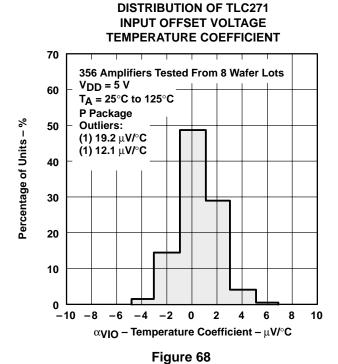


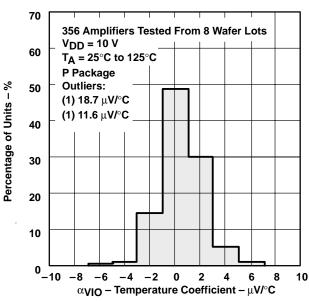
Figure 66



DISTRIBUTION OF TLC271 INPUT OFFSET VOLTAGE 70 905 Amplifiers Tested From 6 Wafer Lots $V_{DD} = 10 V$ 60 T_A = 25°C P Package Percentage of Units – % 50 40 30 20 10 0 -5 -3 -2 -1 02 4 5 -4 V_{IO} - Input Offset Voltage - mV

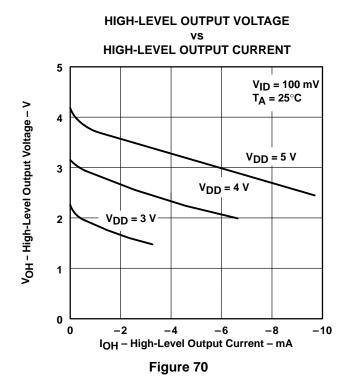
Figure 67

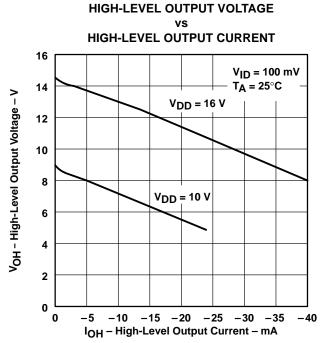
DISTRIBUTION OF TLC271 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT



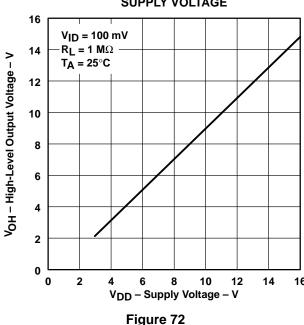
[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.







HIGH-LEVEL OUTPUT VOLTAGE vs SUPPLY VOLTAGE



HIGH-LEVEL OUTPUT VOLTAGE vs

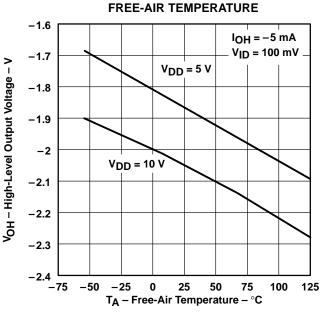


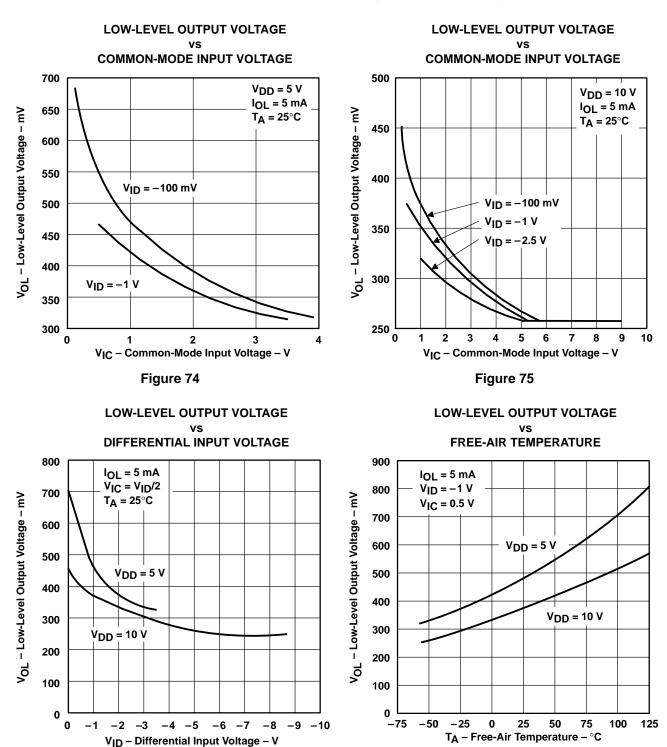
Figure 73

[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



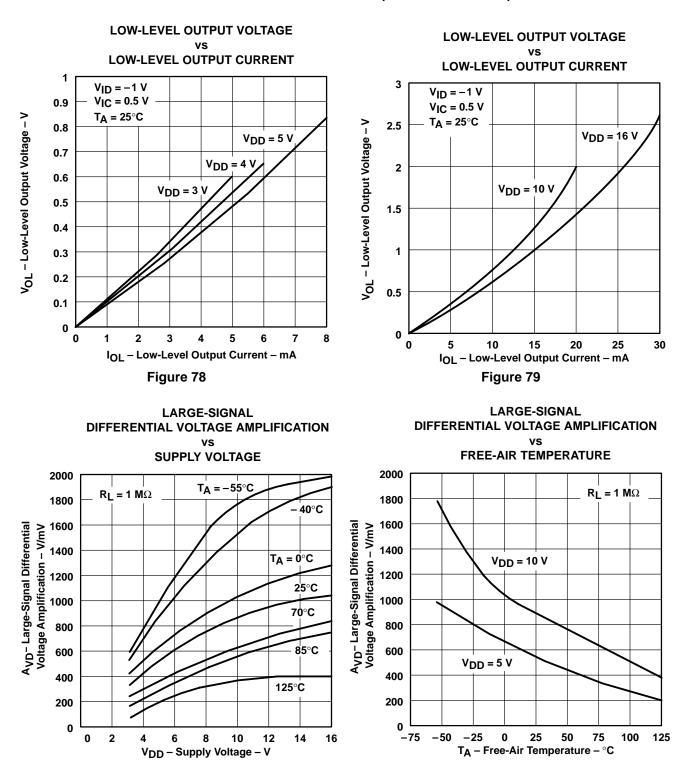
Figure 77

TYPICAL CHARACTERISTICS (LOW-BIAS MODE)†





[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



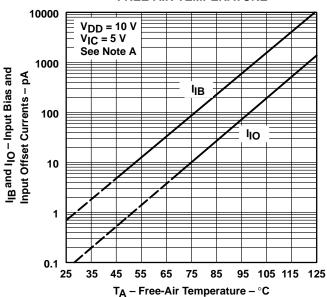
[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

Figure 81



INPUT BIAS CURRENT AND INPUT OFFSET CURRENT

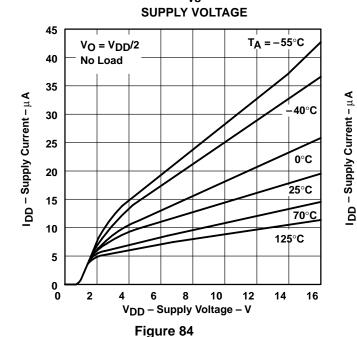
vs FREE-AIR TEMPERATURE



NOTE A: The typical values of input bias current and input offset current below 5 pA were determined mathematically.

Figure 82

SUPPLY CURRENT



MAXIMUM INPUT VOLTAGE

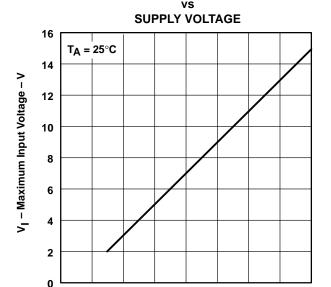


Figure 83

6

2

0

SUPPLY CURRENT

VS EDEE_AID TEMPEDATIIDE

8

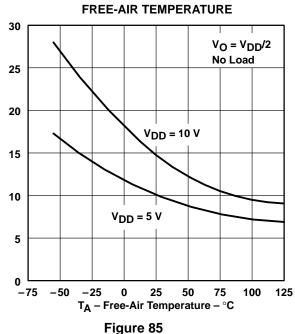
V_{DD} – Supply Voltage – V

10

12

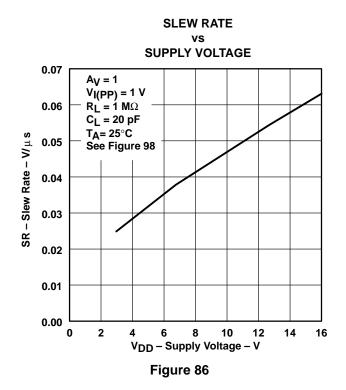
14

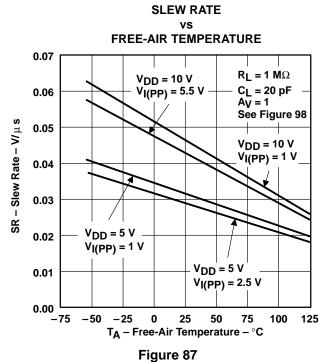
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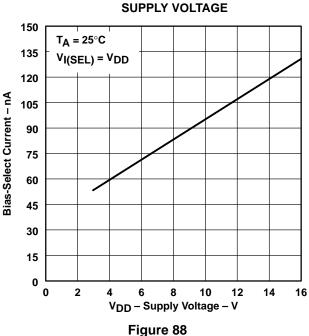
† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



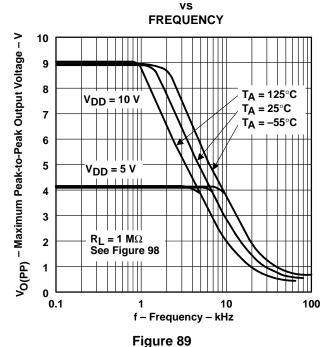




BIAS-SELECT CURRENT
vs

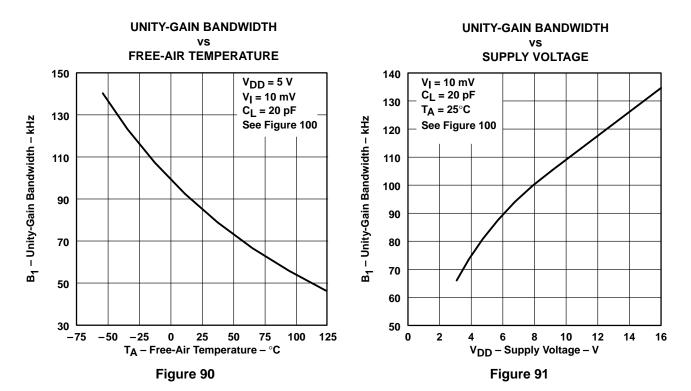


MAXIMUM PEAK-TO-PEAK OUTPUT VOLTAGE

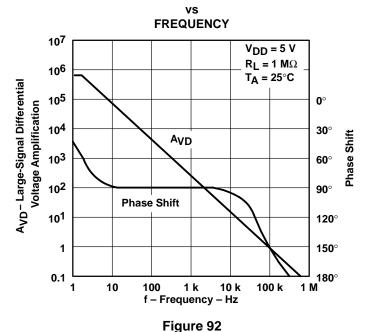


[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.





LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT



[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

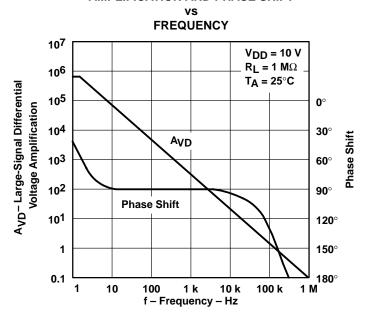
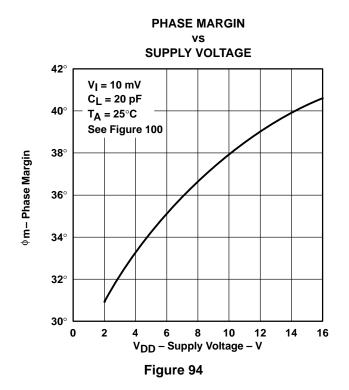
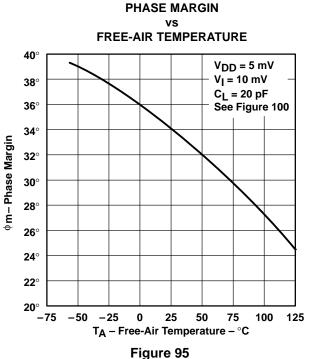


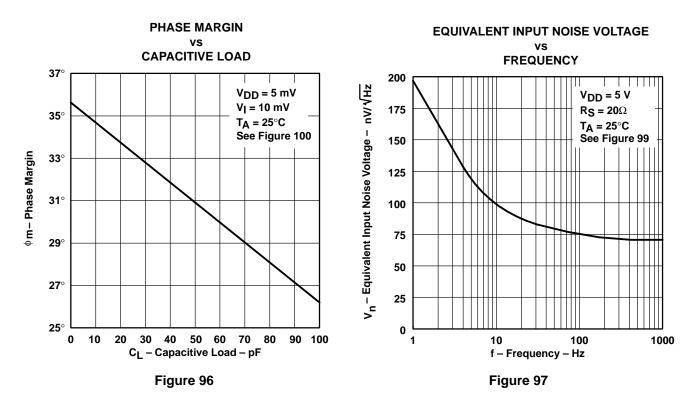
Figure 93





[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.





[†] Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

PARAMETER MEASUREMENT INFORMATION

single-supply versus split-supply test circuits

Because the TLC271 is optimized for single-supply operation, circuit configurations used for the various tests often present some inconvenience since the input signal, in many cases, must be offset from ground. This inconvenience can be avoided by testing the device with split supplies and the output load tied to the negative rail. A comparison of single-supply versus split-supply test circuits is shown below. The use of either circuit gives the same result.

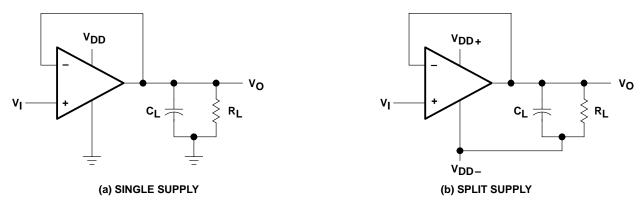


Figure 98. Unity-Gain Amplifier

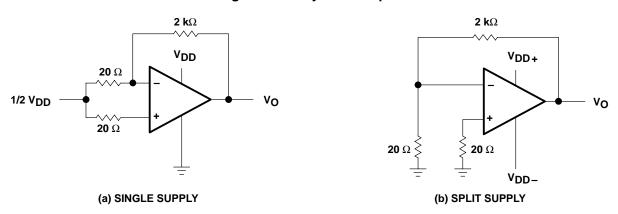


Figure 99. Noise-Test Circuit

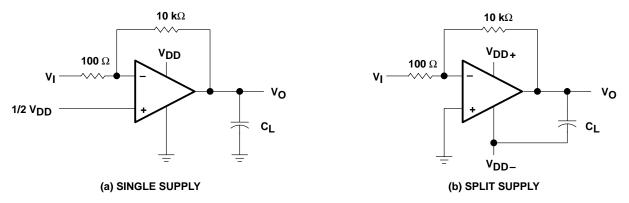


Figure 100. Gain-of-100 Inverting Amplifier



PARAMETER MEASUREMENT INFORMATION

input bias current

Because of the high input impedance of the TLC271 operational amplifiers, attempts to measure the input bias current can result in erroneous readings. The bias current at normal room ambient temperature is typically less than 1 pA, a value that is easily exceeded by leakages on the test socket. Two suggestions are offered to avoid erroneous measurements:

- 1. Isolate the device from other potential leakage sources. Use a grounded shield around and between the device inputs (see Figure 101). Leakages that would otherwise flow to the inputs are shunted away.
- Compensate for the leakage of the test socket by actually performing an input bias current test (using a picoammeter) with no device in the test socket. The actual input bias current can then be calculated by subtracting the open-socket leakage readings from the readings obtained with a device in the test socket.

One word of caution: many automatic testers as well as some bench-top operational amplifier testers us the servo-loop technique with a resistor in series with the device input to measure the input bias current (the voltage drop across the series resistor is measured and the bias current is calculated). This method requires that a device be inserted into the test socket to obtain a correct reading; therefore, an open-socket reading is not feasible using this method.

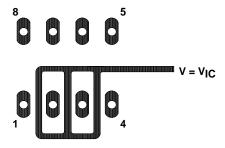


Figure 101. Isolation Metal Around Device inputs (JG and P packages)

low-level output voltage

To obtain low-supply-voltage operation, some compromise is necessary in the input stage. This compromise results in the device low-level output being dependent on both the common-mode input voltage level as well as the differential input voltage level. When attempting to correlate low-level output readings with those quoted in the electrical specifications, these two conditions should be observed. If conditions other than these are to be used, please refer to the Typical Characteristics section of this data sheet.

input offset voltage temperature coefficient

Erroneous readings often result from attempts to measure temperature coefficient of input offset voltage. This parameter is actually a calculation using input offset voltage measurements obtained at two different temperatures. When one (or both) of the temperatures is below freezing, moisture can collect on both the device and the test socket. This moisture results in leakage and contact resistance which can cause erroneous input offset voltage readings. The isolation techniques previously mentioned have no effect on the leakage since the moisture also covers the isolation metal itself, thereby rendering it useless. It is suggested that these measurements be performed at temperatures above freezing to minimize error.



PARAMETER MEASUREMENT INFORMATION

full-power response

Full-power response, the frequency above which the amplifier slew rate limits the output voltage swing, is often specified two ways: full-linear response and full-peak response. The full-linear response is generally measuredby monitoring the distortion level of the output while increasing the frequency of a sinusoidal input signal until the maximum frequency is found above which the output contains significant distortion. The full-peak response is defined as the maximum output frequency, without regard to distortion, above which full peak-to-peak output swing cannot be maintained.

Because there is no industry-wide accepted value for significant distortion, the full-peak response is specified in this data sheet and is measured using the circuit of Figure 98. The initial setup involves the use of a sinusoidal input to determine the maximum peak-to-peak output of the device (the amplitude of the sinusoidal wave is increased until clipping occurs). The sinusoidal wave is then replaced with a square wave of the same amplitude. The frequency is then increased until the maximum peak-to-peak output can no longer be maintained (Figure 102). A square wave is used to allow a more accurate determination of the point at which the maximum peak-to-peak output is reached.

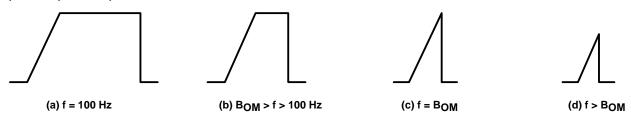


Figure 102. Full-Power-Response Output Signal

test time

Inadequate test time is a frequent problem, especially when testing CMOS devices in a high-volume, short-test-time environment. Internal capacitances are inherently higher in CMOS than in bipolar and BiFET devices, and require longer test times than their bipolar and BiFET counterparts. The problem becomes more pronounced with reduced supply levels and lower temperatures.

APPLICATION INFORMATION

single-supply operation

While the TLC271 performs well using dual power supplies (also called balanced or split supplies), the design is optimized for single-supply operation. This includes an input common mode voltage range that encompasses ground as well as an output voltage range that pulls down to ground. The supply voltage range extends down to 3 V (C-suffix types), thus allowing operation with supply levels commonly available for TTL and HCMOS; however, for maximum dynamic range, 16-V single-supply operation is recommended.

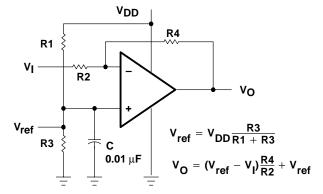


Figure 103. Inverting Amplifier With Voltage Reference



APPLICATION INFORMATION

single-supply operation (continued)

Many single-supply applications require that a voltage be applied to one input to establish a reference level that is above ground. A resistive voltage divider is usually sufficient to establish this reference level (see Figure 103). The low input bias current consumption of the TLC271 permits the use of very large resistive values to implement the voltage divider, thus minimizing power consumption.

The TLC271 works well in conjunction with digital logic; however, when powering both linear devices and digital logic from the same power supply, the following precautions are recommended:

- 1. Power the linear devices from separate bypassed supply lines (see Figure 104); otherwise, the linear device supply rails can fluctuate due to voltage drops caused by high switching currents in the digital logic.
- 2. Use proper bypass techniques to reduce the probability of noise-induced errors. Single capacitive decoupling is often adequate; however, RC decoupling may be necessary in high-frequency applications.

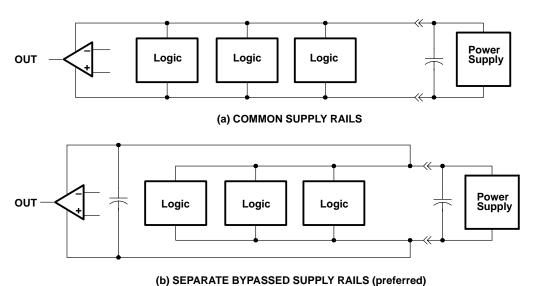


Figure 104. Common Versus Separate Supply Rails



APPLICATION INFORMATION

input offset voltage nulling

The TLC271 offers external input offset null control. Nulling of the input off set voltage may be achieved by adjusting a 25-k Ω potentiometer connected between the offset null terminals with the wiper Connected as shown in Figure 105. The amount of nulling range varies with the bias selection. In the high-bias mode, the nulling range allows the maximum offset voltage specified to be trimmed to zero. In low-bias and medium-bias modes, total nulling may not be possible.

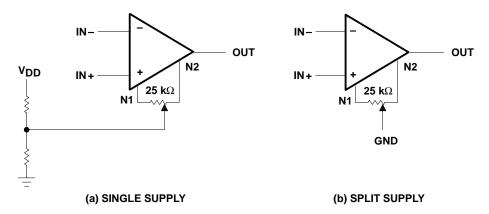


Figure 105. Input Offset Voltage Null Circuit

bias selection

Bias selection is achieved by connecting the bias select pin to one of the three voltage levels (see Figure 106). For medium-bias applications, R is recommended that the bias select pin be connected to the mid-point between the supply rails. This is a simple procedure in split-supply applications, since this point is ground. In single-supply applications, the medium-bias mode necessitates using a voltage divider as indicated. The use of large-value resistors in the voltage divider reduces the current drain of the divider from the supply line. However, large-value resistors used in conjunction with a large-value capacitor requires significant time to charge up to the supply midpoint after the supply is switched on. A voltage other than the midpoint may be used if it is within the voltages specified in the table of Figure 106.

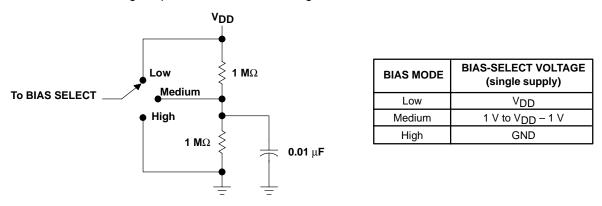


Figure 106. Bias Selection for Single-Supply Applications



APPLICATION INFORMATION

input characteristics

The TLC271 is specified with a minimum and a maximum input voltage that, if exceeded at either input, could cause the device to malfunction. Exceeding this specified range is a common problem, especially in single-supply operation. Note that the lower range limit includes the negative rail, while the upper range limit is specified at $V_{DD} - 1$ V at $T_A = 25$ °C and at $V_{DD} - 1.5$ V at all other temperatures.

The use of the polysilicon-gate process and the careful input circuit design gives the TLC271 very good input offset voltage drift characteristics relative to conventional metal-gate processes. Offset voltage drift in CMOS devices is highly influenced by threshold voltage shifts caused by polarization of the phosphorus dopant implanted in the oxide. Placing the phosphorus dopant in a conductor (such as a polysilicon gate) alleviates the polarization problem, thus reducing threshold voltage shifts by more than an order of magnitude. The offset voltage drift with time has been calculated to be typically $0.1 \,\mu\text{V/month}$, including the first month of operation.

Because of the extremely high input impedance and resulting low bias current requirements, the TLC271 is well suited for low-level signal processing; however, leakage currents on printed circuit boards and sockets can easily exceed bias current requirements and cause a degradation in device performance. It is good practice to include guard rings around inputs (similar to those of Figure 101 in the Parameter Measurement Information section). These guards should be driven from a low-impedance source at the same voltage level as the common-mode input (see Figure 107).

The inputs of any unused amplifiers should be tied to ground to avoid possible oscillation.

noise performance

The noise specifications in operational amplifier circuits are greatly dependent on the current in the first-stage differential amplifier. The low input bias current requirements of the TLC271 results in a very low noise current, which is insignificant in most applications. This feature makes the devices especially favorable over bipolar devices when using values of circuit impedance greater than 50 k Ω , since bipolar devices exhibit greater noise currents.

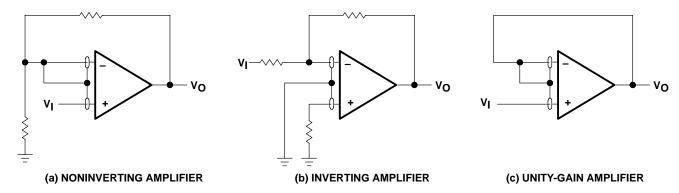


Figure 107. Guard-Ring Schemes

APPLICATION INFORMATION

feedback

Operational amplifier circuits almost always employ feedback, and since feedback is the first prerequisite for oscillation, a little caution is appropriate. Most oscillation problems result from driving capacitive loads and ignoring stray input capacitance. A small-value capacitor connected in parallel with the feedback resistor is an effective remedy (see Figure 108). The value of this capacitor is optimized empirically.

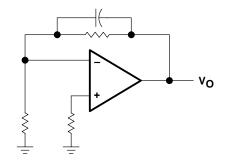


Figure 108. Compensation for Input Capacitance

electrostatic discharge protection

The TLC271 incorporates an internal electrostatic-discharge (ESD) protection circuit that prevents functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2. Care should be exercised, however, when handling these devices as exposure to ESD may result in the degradation of the device parametric performance. The protection circuit also causes the input bias currents to be temperature dependent and have the characteristics of a reverse-biased diode.

latch-up

Because CMOS devices are susceptible to latch-up due to their inherent parasitic thyristors, the TLC271 inputs and output were designed to withstand -100-mA surge currents without sustaining latchup; however, techniques should be used to reduce the chance of latch-up whenever possible. Internal protection diodes should not by design be forward biased. Applied input and output voltage should not exceed the supply voltage by more than 300 mV. Care should be exercised when using capacitive coupling on pulse generators. Supply transients should be shunted by the use of decoupling capacitors (0.1 µF typical) located across the supply rails as close to the device as possible.

The current path established if latch-up occurs is usually between the positive supply rail and ground and can be triggered by surges on the supply lines and/or voltages on either the output or inputs that exceed the supply voltage. Once latch-up occurs, the current flow is limited only by the impedance of the power supply and the forward resistance of the parasitic thyristor and usually results in the destruction of the device. The chance of latch-up occurring increases with increasing temperature and supply voltages.

output characteristics

The output stage of the TLC271 is designed to sink and source relatively high amounts of current (see Typical Characteristics). If the output is subjected to a short-circuit condition, this high current capability can cause device damage under certain conditions. Output current capability increases with supply voltage.

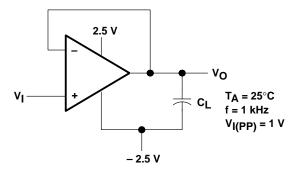


Figure 109. Test Circuit for Output Characteristics



APPLICATION INFORMATION

output characteristics (continued)

All operating characteristics of the TLC271 were measured using a 20-pF load. The devices drive higher capacitive loads; however, as output load capacitance increases, the resulting response pole occurs at lower frequencies, thereby causing ringing, peaking, or even oscillation (see Figures 110, 111, and 112). In many cases, adding some compensation in the form of a series resistor in the feedback loop alleviates the problem.

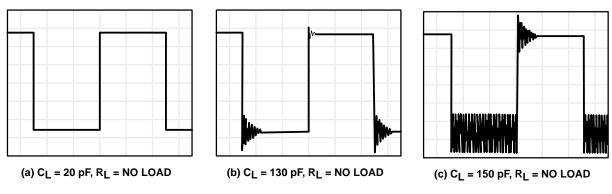


Figure 110. Effect of Capacitive Loads in High-Bias Mode

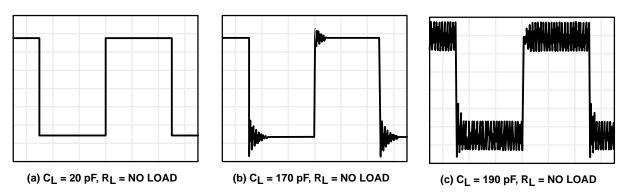


Figure 111. Effect of Capacitive Loads in Medium-Bias Mode



Figure 112. Effect of Capacitive Loads in Low-Bias Mode

APPLICATION INFORMATION

output characteristics (continued)

Although the TLC271 possesses excellent high-level output voltage and current capability, methods are available for boosting this capability, if needed. The simplest method involves the use of a pullup resistor (R_P) connected from the output to the positive supply rail (see Figure 113). There are two disadvantages to the use of this circuit. First, the NMOS pulldown transistor, N4 (see equivalent schematic) must sink a comparatively large amount of current. In this circuit, N4 behaves like a linear resistor with an on-resistance between approximately 60 Ω and 180 Ω , depending on how hard the operational amplifier input is driven. With very low values of R_P , a voltage offset from 0 V at the output occurs. Secondly, pullup resistor RP acts as a drain load to N4 and the gain of the operational amplifier is reduced at output voltage levels where N5 is not supplying the output current.

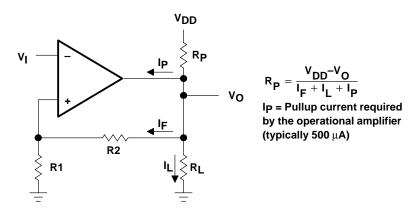
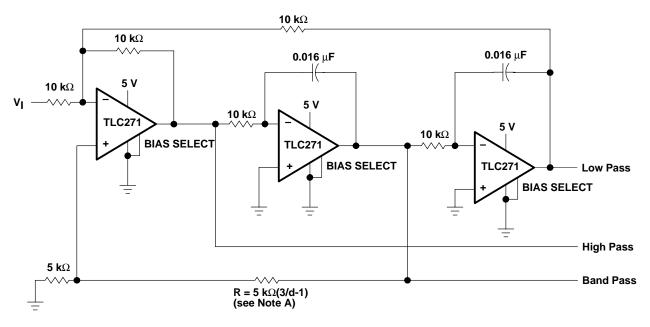


Figure 113. Resistive Pullup to Increase VOH



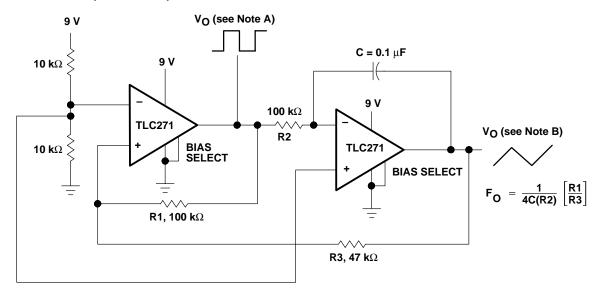
NOTE B: d = damping factor, I/O

Figure 114. State-Variable Filter



APPLICATION INFORMATION

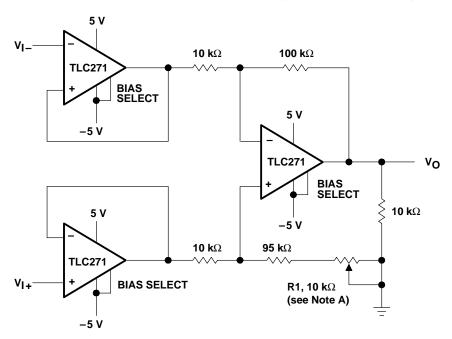
output characteristics (continued)



NOTES: A. $V_{O(PP)} = 8 \text{ V}$ B. $V_{O(PP)} = 4 \text{ V}$

Figure 115. Single-Supply Function Generator

APPLICATION INFORMATION (HIGH-BIAS MODE)



NOTE A: CMRR adjustment must be noninductive.

Figure 116. Low-Power Instrumentation Amplifier

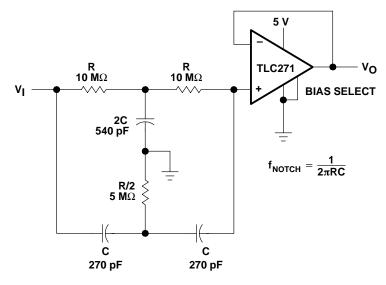
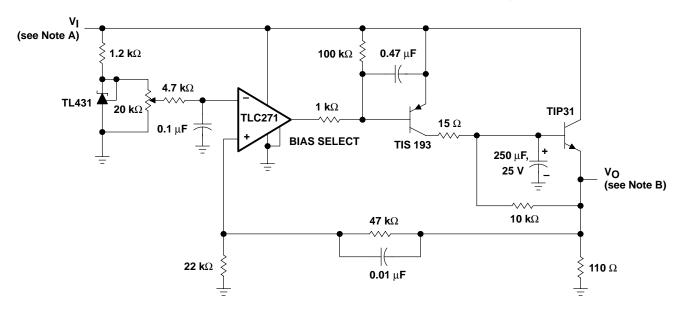


Figure 117. Single-Supply Twin-T Notch Filter



APPLICATION INFORMATION (HIGH-BIAS MODE)



NOTES: A. $V_I = 3.5$ to 15 V B. $V_O = 2.0$ V, 0 to 1 A

Figure 118. Logic-Array Power Supply

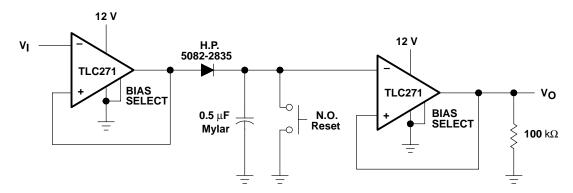
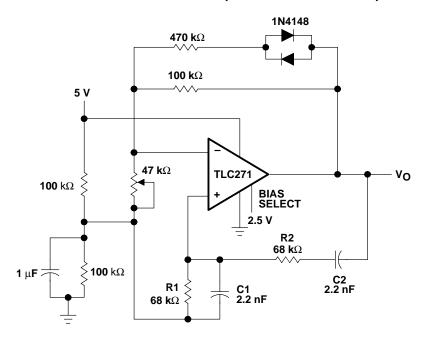


Figure 119. Positive-Peak Detector

APPLICATION INFORMATION (MEDIUM-BIAS MODE)



NOTES: A.
$$V_{O(PP)} = 2 V$$
 B. $f_{O} = \frac{1}{2\pi \sqrt{R1R2C1C2}}$

Figure 120. Wein Oscillator

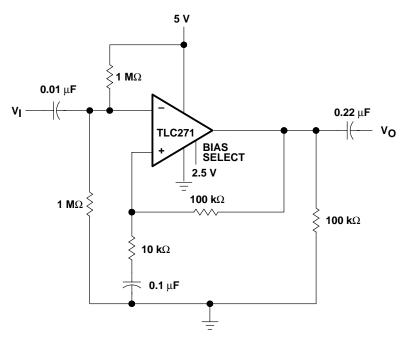
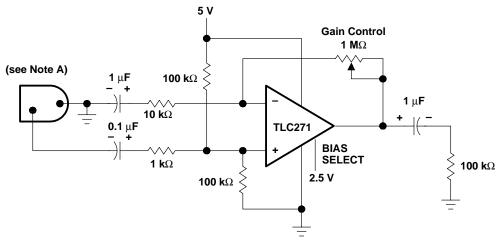


Figure 121. Single-Supply AC Amplifier

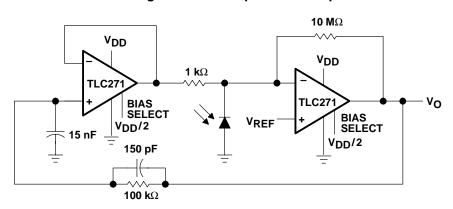


APPLICATION INFORMATION (MEDIUM-BIAS MODE)



NOTE A: Low to medium impedance dynamic mike

Figure 122. Microphone Preamplifier



NOTES: A. NOTES: $V_{DD} = 4 \text{ V to } 15 \text{ V}$ B. $V_{ref} = 0 \text{ V to } V_{DD} - 2 \text{ V}$

Figure 123. Photo-Diode Amplifier With Ambient Light Rejection

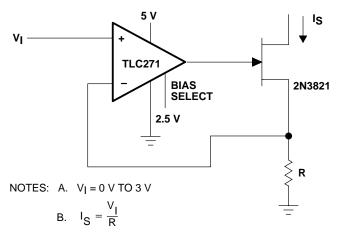
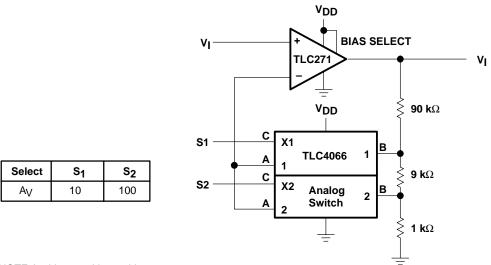


Figure 124. Precision Low-Current Sink



APPLICATION INFORMATION (LOW-BIAS MODE)



NOTE A: $V_{DD} = 5 \text{ V to } 12 \text{ V}$

Figure 125. Amplifier With Digital Gain Selection

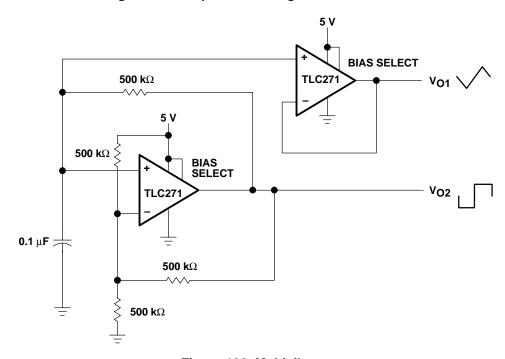
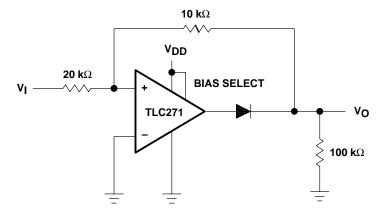


Figure 126. Multivibrator

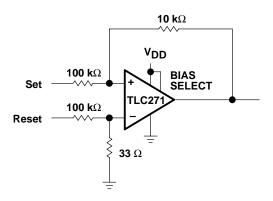


APPLICATION INFORMATION (LOW-BIAS MODE)



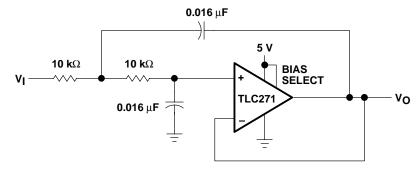
NOTE A: $V_{DD} = 5 \text{ V to } 16 \text{ V}$

Figure 127. Full-Wave Rectifier



NOTE A: $V_{DD} = 5 \text{ V to } 16 \text{ V}$

Figure 128. Set/Reset Flip-Flop



NOTE A: Normalized to FC = 1 kHz and RL = 10 k Ω

Figure 129. Two-Pole Low-Pass Butterworth Filter





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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLC271ACD	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	271AC	
TLC271ACDR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	271AC	
TLC271ACP	LIFEBUY	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	TLC271ACP	
TLC271ACPS	LIFEBUY	SO	PS	8	80	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271A	
TLC271ACPSR	LIFEBUY	so	PS	8	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271A	
TLC271AID	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	271Al	
TLC271AIDG4	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	271AI	
TLC271AIDR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	271AI	
TLC271AIP	LIFEBUY	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	TLC271AIP	
TLC271BCD	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	271BC	
TLC271BCDR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	271BC	
TLC271BCP	LIFEBUY	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	TLC271BCP	
TLC271BCPS	LIFEBUY	so	PS	8	80	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271B	
TLC271BID	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	271BI	
TLC271BIDG4	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	271BI	
TLC271BIDR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	271BI	
TLC271BIP	LIFEBUY	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	TLC271BIP	
TLC271CD	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	271C	
TLC271CDR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	271C	
TLC271CP	LIFEBUY	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	TLC271CP	
TLC271CPS	LIFEBUY	SO	PS	8	80	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271	
TLC271CPSR	LIFEBUY	so	PS	8	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271	
TLC271CPW	LIFEBUY	TSSOP	PW	8	150	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271	
TLC271CPWR	LIFEBUY	TSSOP	PW	8	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271	
TLC271CPWRG4	LIFEBUY	TSSOP	PW	8	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	P271	
TLC271ID	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	2711	
TLC271IDR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	2711	
TLC271IP	LIFEBUY	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	TLC271IP	
TLC271MDR	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	271M	





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Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TLC271MDRG4	LIFEBUY	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	271M	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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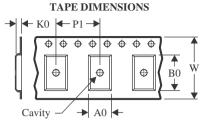




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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

All dimensions are nominal													
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant	
TLC271ACDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1	
TLC271ACPSR	so	PS	8	2000	330.0	16.4	8.35	6.6	2.5	12.0	16.0	Q1	
TLC271AIDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1	
TLC271BCDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1	
TLC271BIDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1	
TLC271CDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1	
TLC271CPSR	so	PS	8	2000	330.0	16.4	8.35	6.6	2.5	12.0	16.0	Q1	
TLC271CPWR	TSSOP	PW	8	2000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1	
TLC271IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1	
TLC271MDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1	



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*All dimensions are nominal

All difficultions are norminal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLC271ACDR	SOIC	D	8	2500	340.5	338.1	20.6
TLC271ACPSR	SO	PS	8	2000	356.0	356.0	35.0
TLC271AIDR	SOIC	D	8	2500	340.5 338.1		20.6
TLC271BCDR	SOIC	D	8	2500	340.5 338.1		20.6
TLC271BIDR	SOIC	D	8	2500	340.5	338.1	20.6
TLC271CDR	SOIC	D	8	2500	340.5	338.1	20.6
TLC271CPSR	SO	PS	8	2000	367.0	367.0	38.0
TLC271CPWR	TSSOP	PW	8	2000	356.0	356.0	35.0
TLC271IDR	SOIC	D	8	2500	340.5 338.1		20.6
TLC271MDR	SOIC	D	8	2500	350.0	350.0	43.0



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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TLC271ACD	D	SOIC	8	75	507	8	3940	4.32
TLC271ACP	Р	PDIP	8	50	506	13.97	11230	4.32
TLC271ACPS	PS	SOP	8	80	530	10.5	4000	4.1
TLC271AID	D	SOIC	8	75	507	8	3940	4.32
TLC271AIDG4	D	SOIC	8	75	507	8	3940	4.32
TLC271AIP	Р	PDIP	8	50	506	13.97	11230	4.32
TLC271BCD	D	SOIC	8	75	507	8	3940	4.32
TLC271BCP	Р	PDIP	8	50	506	13.97	11230	4.32
TLC271BCPS	PS	SOP	8	80	530	10.5	4000	4.1
TLC271BID	D	SOIC	8	75	507	8	3940	4.32
TLC271BIDG4	D	SOIC	8	75	507	8	3940	4.32
TLC271BIP	Р	PDIP	8	50	506	13.97	11230	4.32
TLC271CD	D	SOIC	8	75	507	8	3940	4.32
TLC271CP	Р	PDIP	8	50	506	13.97	11230	4.32
TLC271CPS	PS	SOP	8	80	530	10.5	4000	4.1
TLC271CPW	PW	TSSOP	8	150	530	10.2	3600	3.5
TLC271ID	D	SOIC	8	75	507	8	3940	4.32
TLC271IP	Р	PDIP	8	50	506	13.97	11230	4.32



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.

PS (R-PDSO-G8)

PLASTIC SMALL OUTLINE



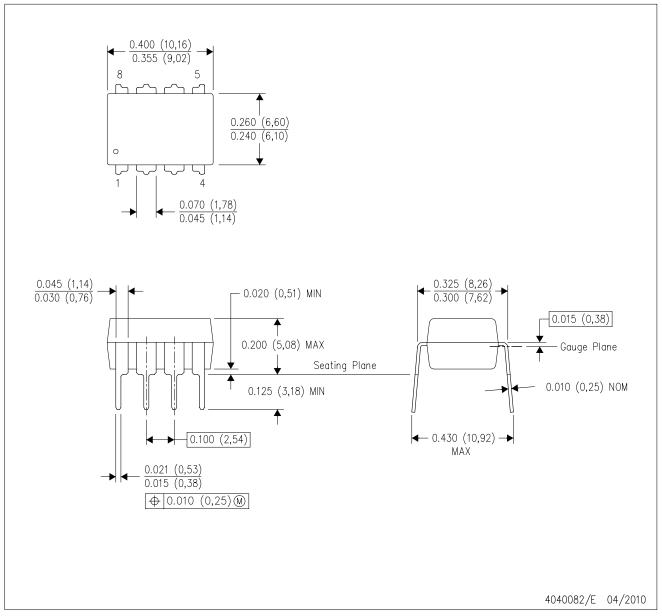
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC—7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



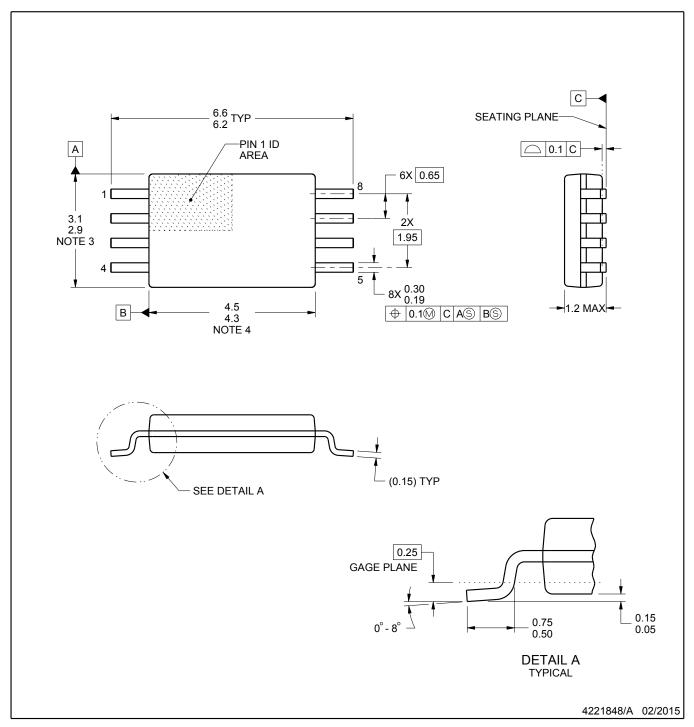
NOTES: A. All lir

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001 variation BA.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153, variation AA.



SMALL OUTLINE PACKAGE

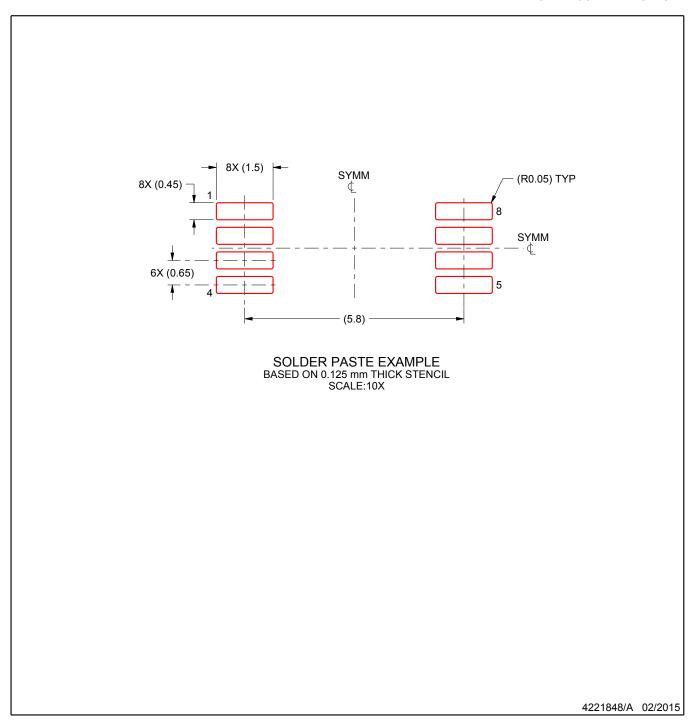


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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